

Extended images in action

(efficient WEMVA via randomized probing)

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Motivation

- *initial model for FWI*
- computation of *full*-subsurface offset volumes is computationally *prohibitively* expensive
(storage & computation time)
- can't form full E but *action* on (random) vectors allows us to get information from *all* or *subsets* of *subsurface points*

Extended images

- Given two-way wave equations, source and receiver wavefields are defined as

$$\begin{aligned}H(\mathbf{m})U &= P_s^T Q \\ H(\mathbf{m})^* V &= P_r^T D\end{aligned}$$

where

$H(\mathbf{m})$: discretization of the Helmholtz operator

Q : source

D : data matrix

P_s, P_r : samples the wavefield at the source and receiver positions

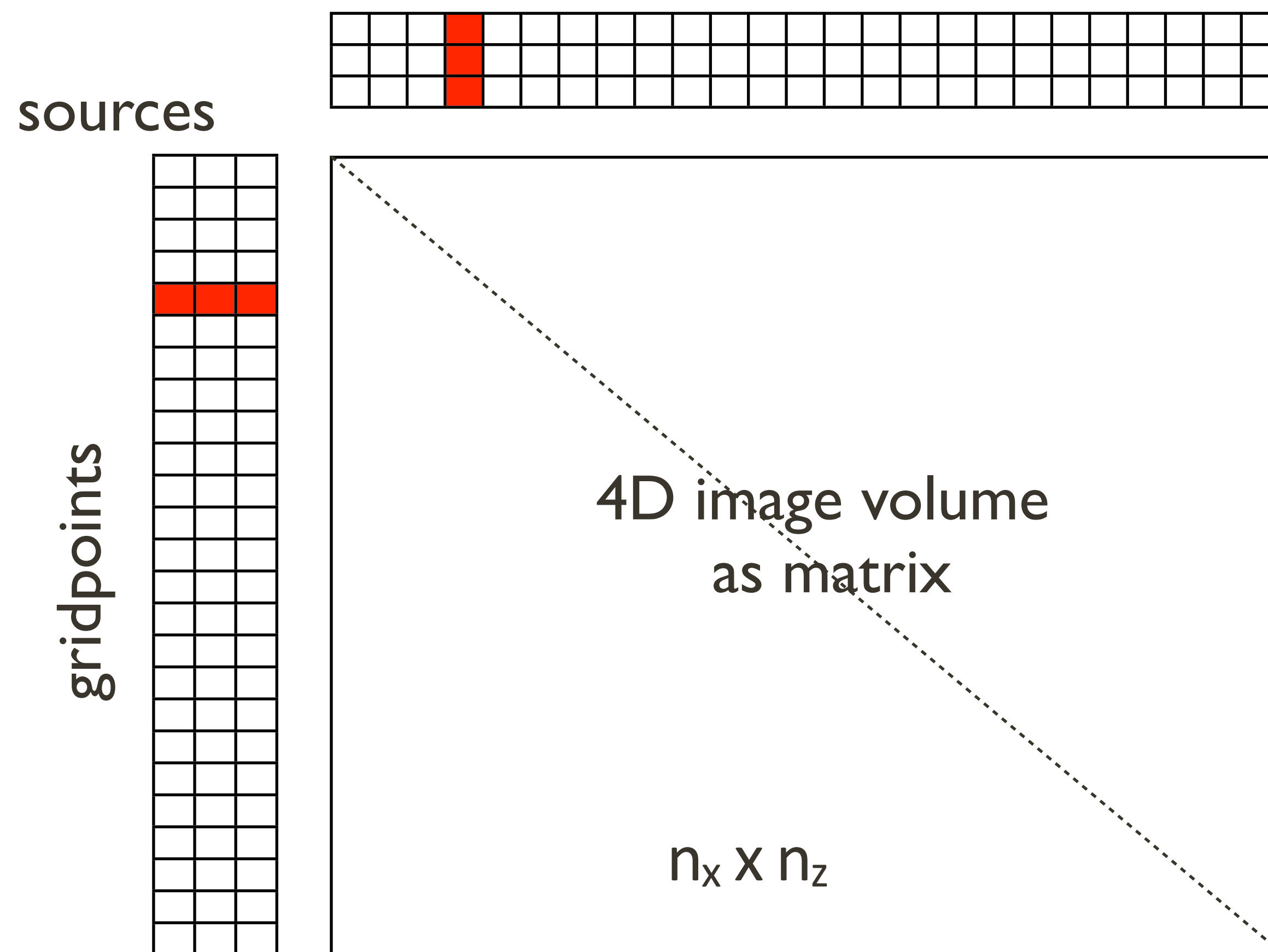
\mathbf{m} : slowness

Extended images

- Organize wavefields in monochromatic data *matrices* where each *column* represents a *common* shot gather
- Express *image volume tensor* for *single* frequency as a *matrix*

$$E = UV^*$$

Extended images



Extended images

- Too expensive to compute (*storage and computational time*)
- Instead, *probe* volume with *tall* matrix $W = [\mathbf{w}_1, \dots, \mathbf{w}_l]$

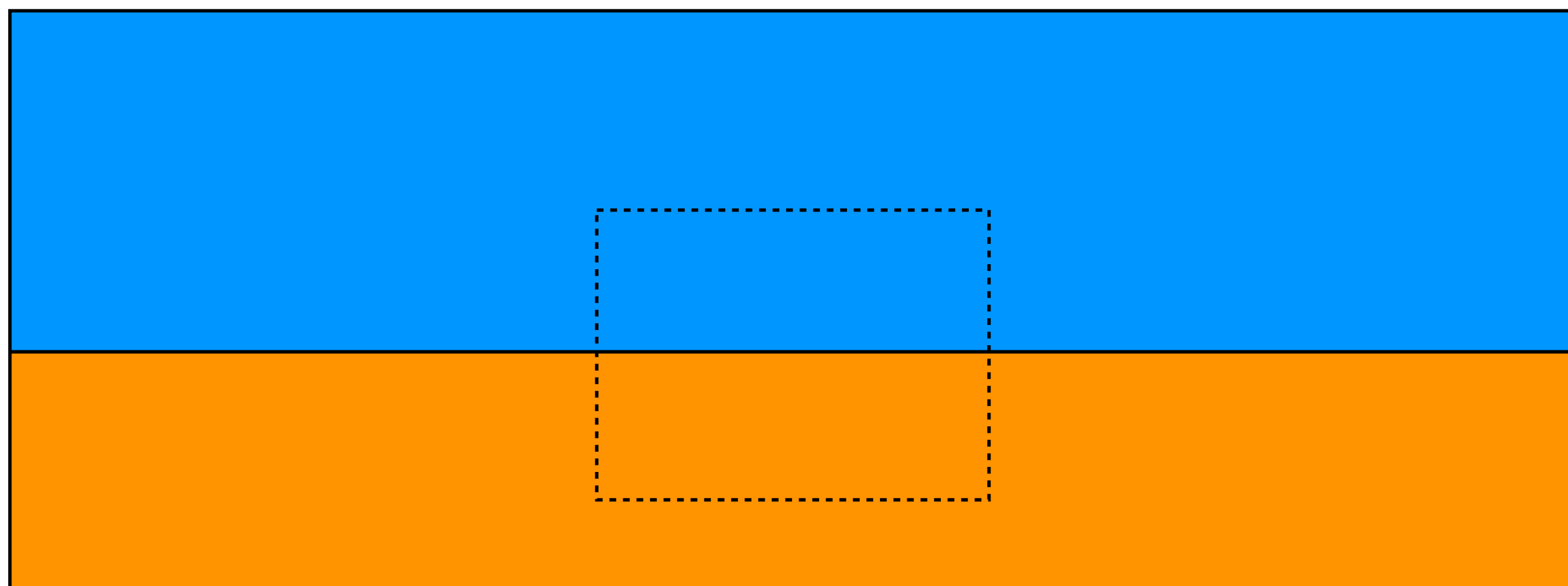
VAN LEEUWEN 2012

$$\tilde{E} = EW = H^{-1}P_s^T QD^* P_r H^{-1}W$$

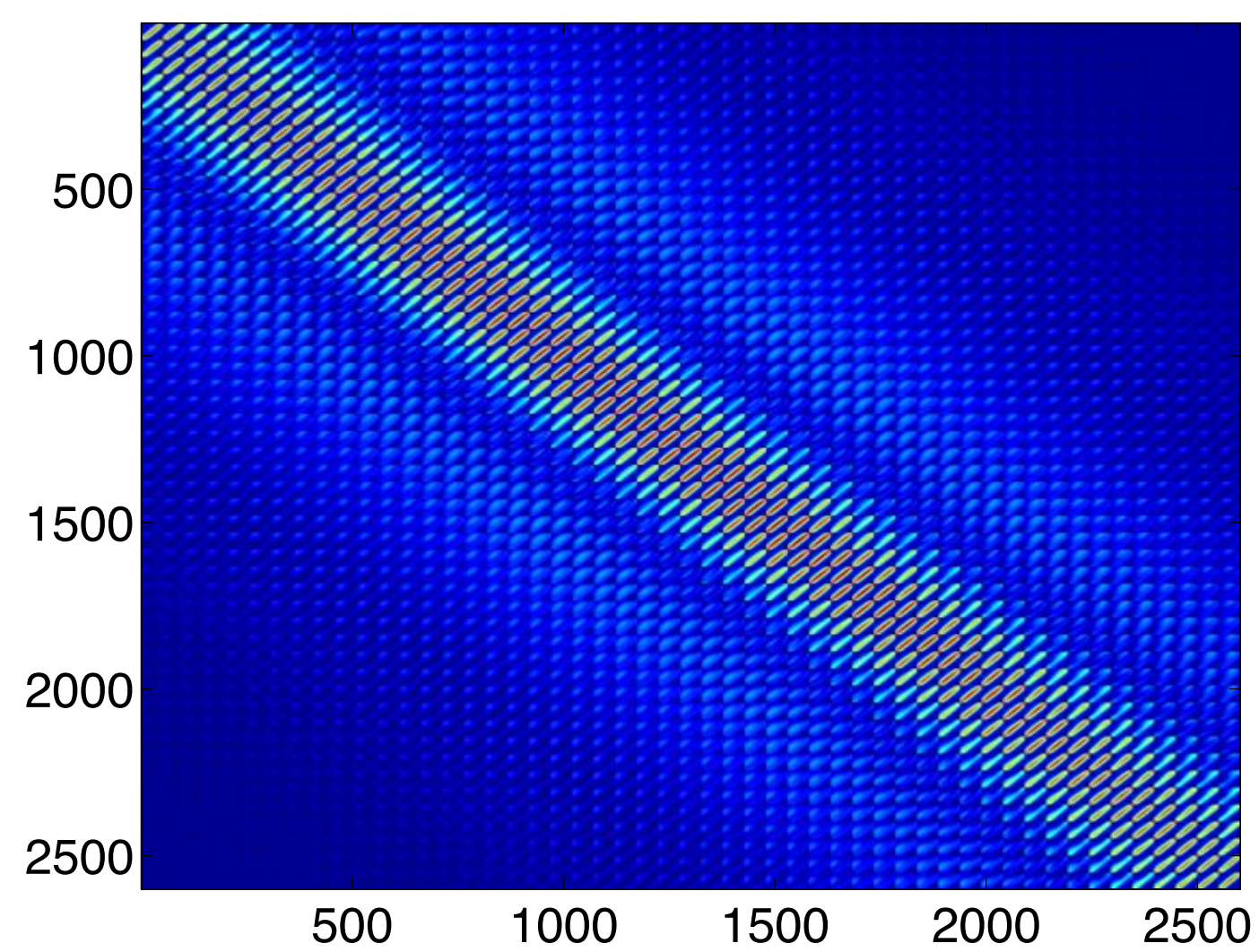
where $\mathbf{w}_i = [0, \dots, 0, 1, 0, \dots, 0]$ represents *single* scattering points

Extended images

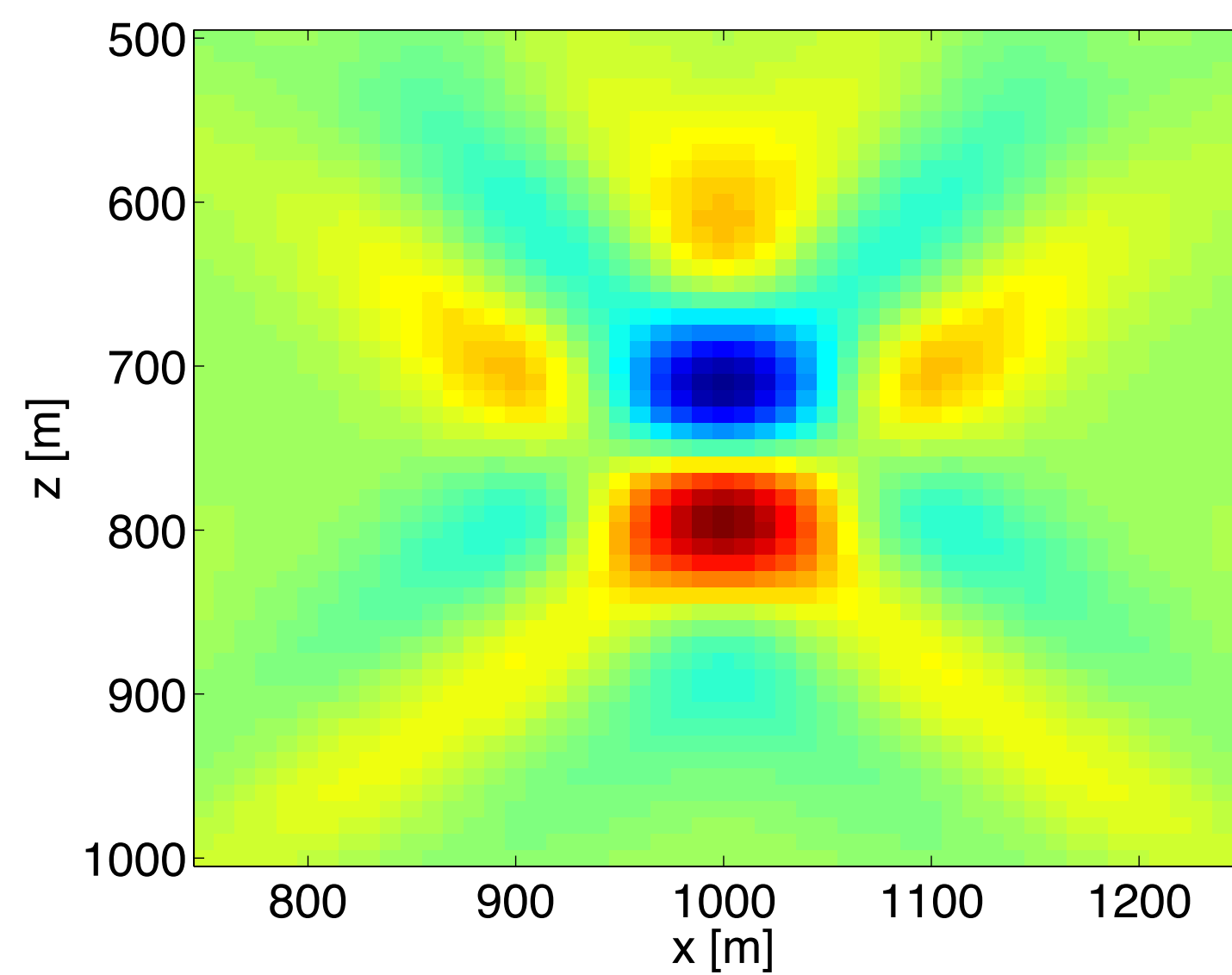
example for *one* layer



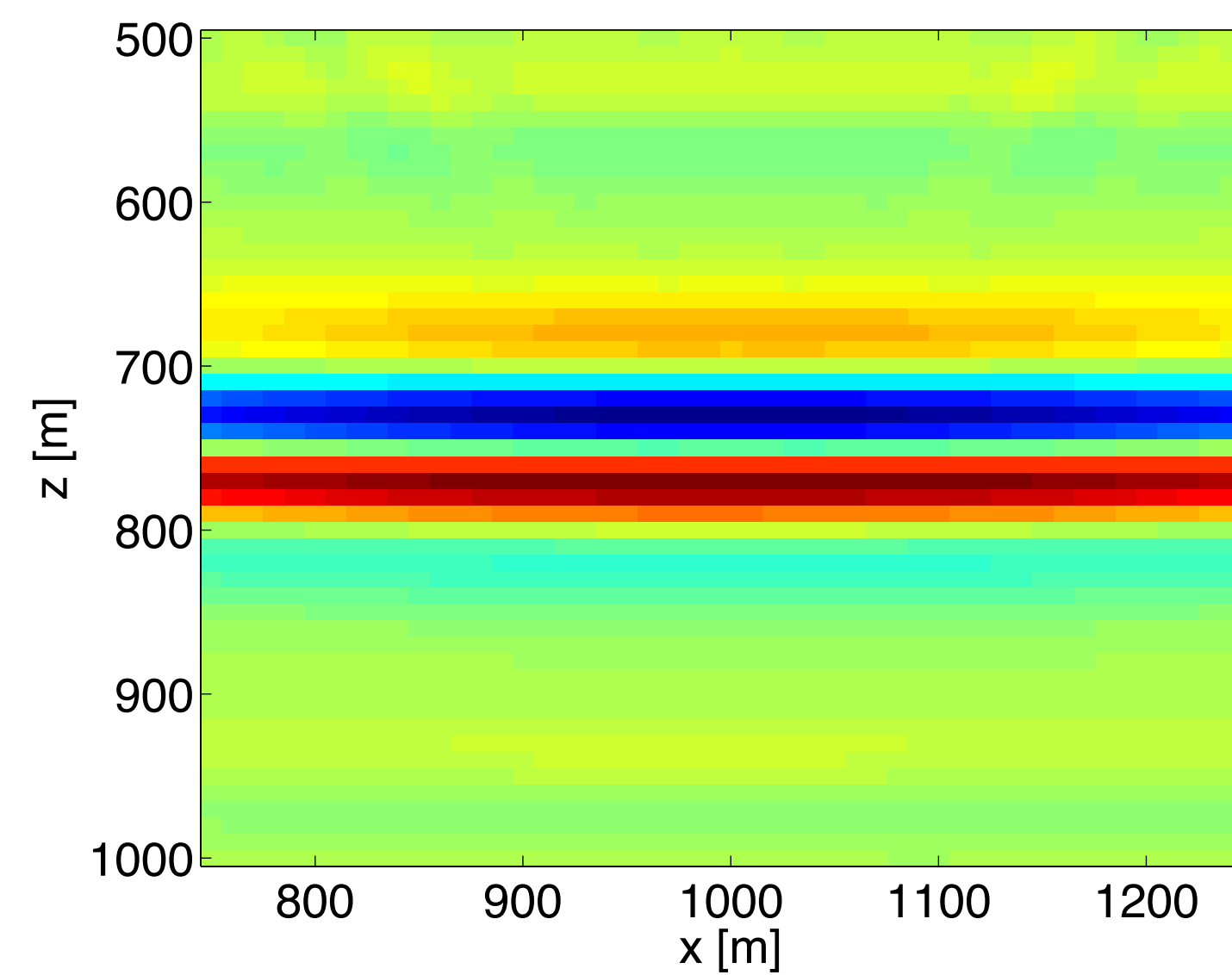
Extended images



full matrix



one column



diagonal

Take-away message

Computational costs

Full subsurface offset extended images:

	# of PDE solves	“flops for correlations”
conventional	$2N_s$	$N_s \times N_h$
mat-vecs	$2N_x$	$N_s \times N_r$

N_s - # of sources

N_r - # of receivers

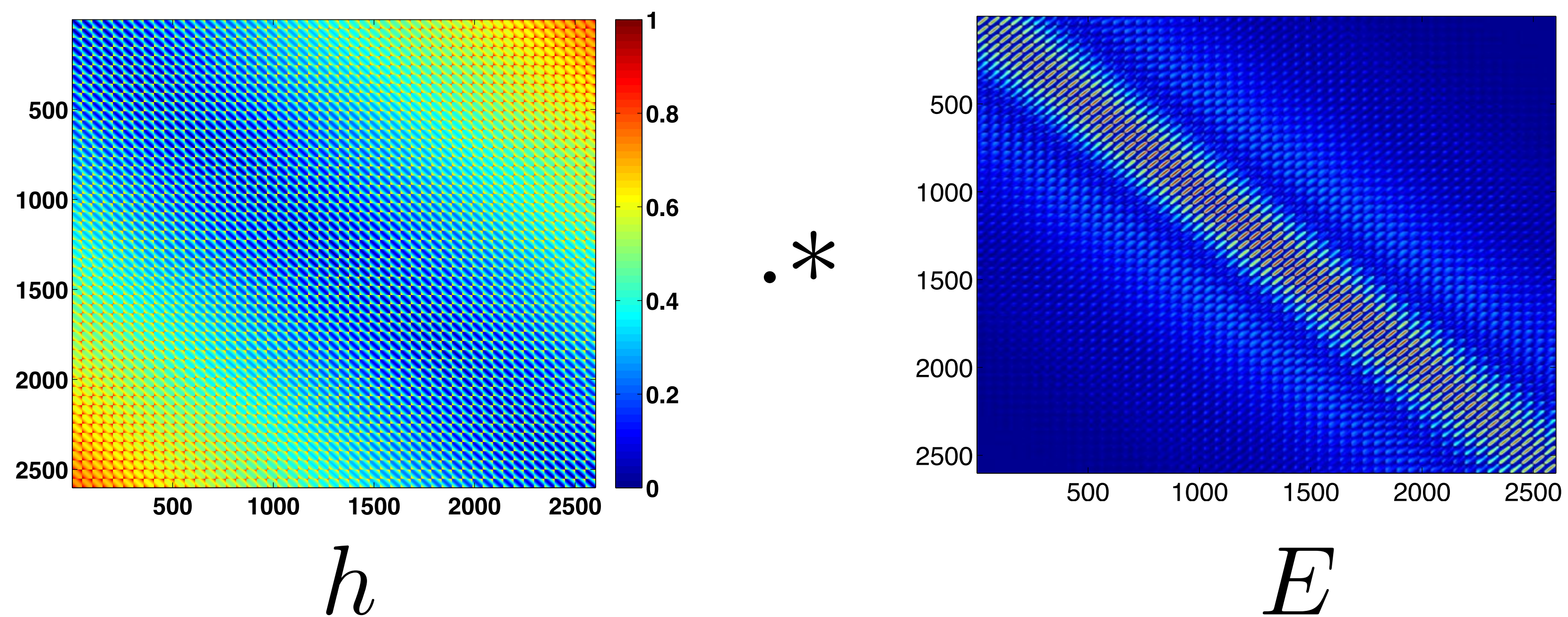
N_h - # of subsurface offsets

N_x - # of sample points

Biondo & Symes, '04 , Symes 2008, Sava & Vasconcelos, '11

WEMVA

[conventional method]

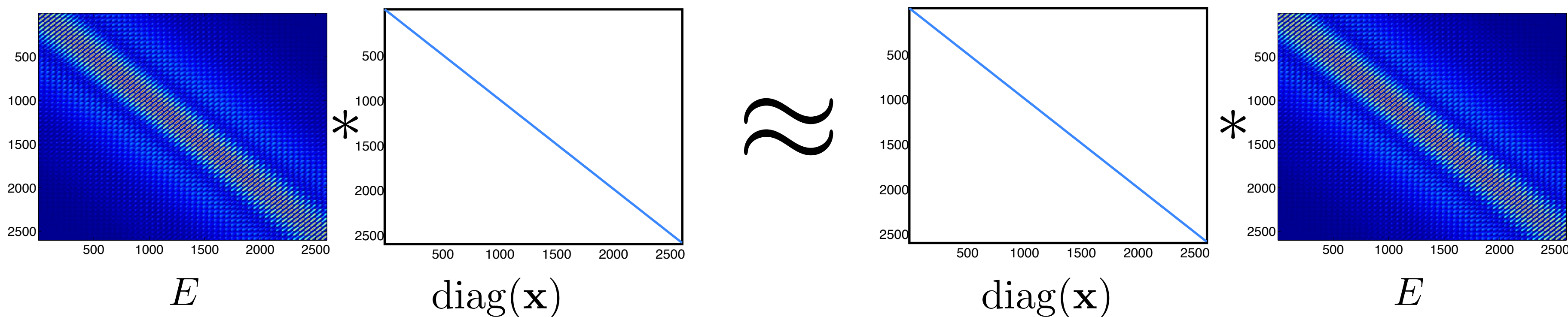


$\bullet *$ stand for element-wise multiplication

Focusing

[propose method] VAN LEEUWEN 2012

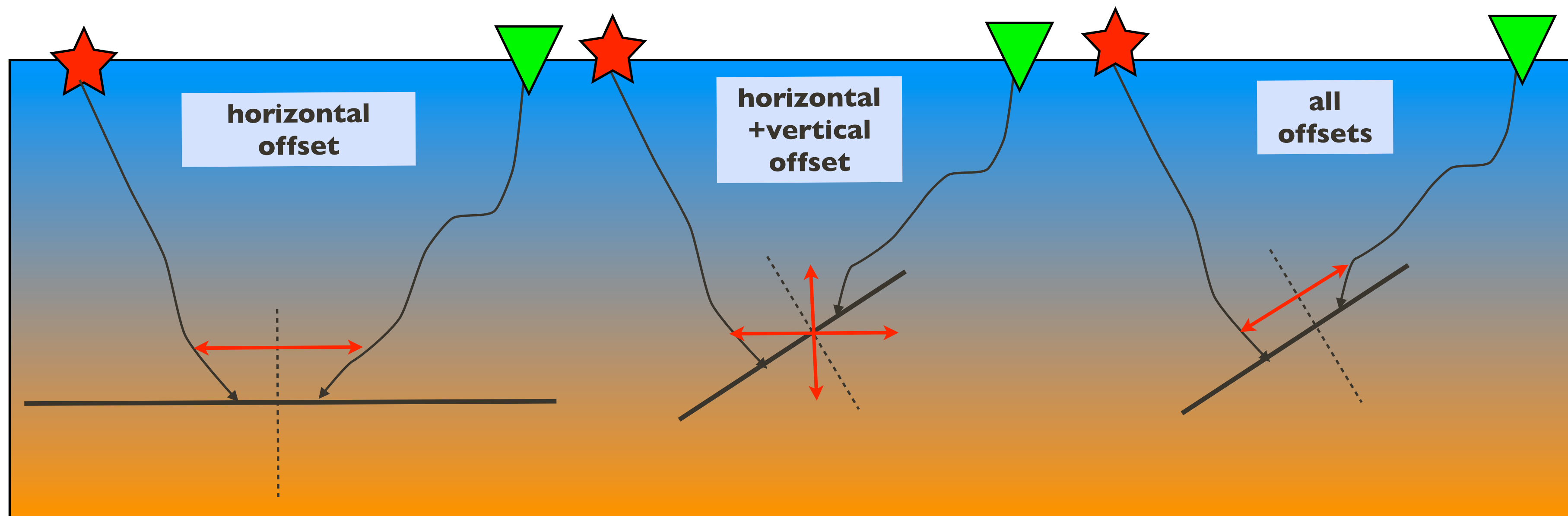
$$E \text{diag}(\mathbf{x}) \approx \text{diag}(\mathbf{x}) E$$



$*$ matrix-matrix multiplication

Focusing

where x represents horizontal, vertical or all offset.



Fast WEMVA w/ randomized probing

- Measure the error in some norm [VAN LEEUWEN 2012](#)

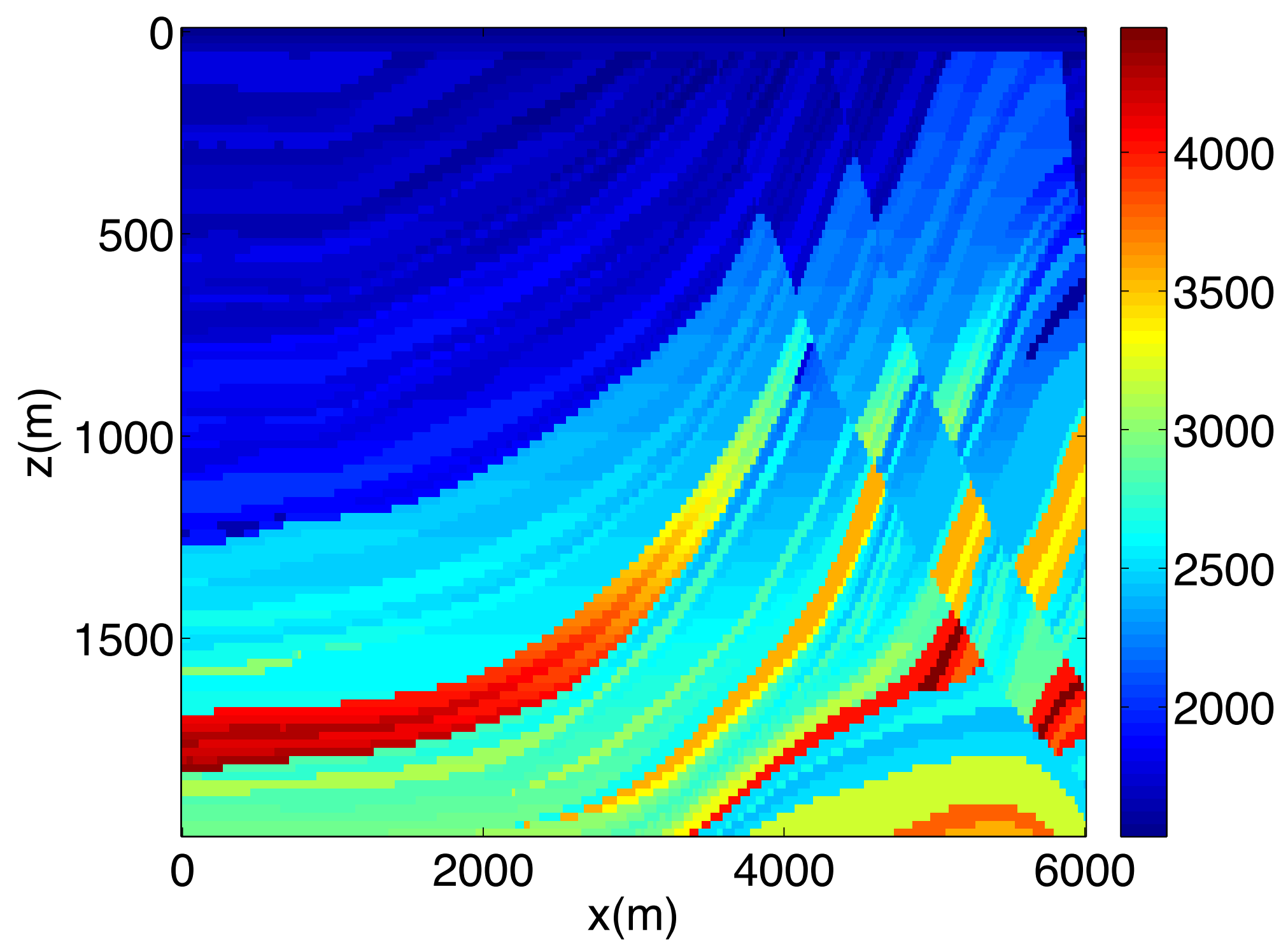
$$\min_{\mathbf{m}} \|\mathbf{E}(\mathbf{m})\text{diag}(\mathbf{x}) - \text{diag}(\mathbf{x})\mathbf{E}(\mathbf{m})\|_F^2?$$

- The *Frobenius* norm can be estimated via randomized trace estimation : [Avron and Toledo, 2011](#)

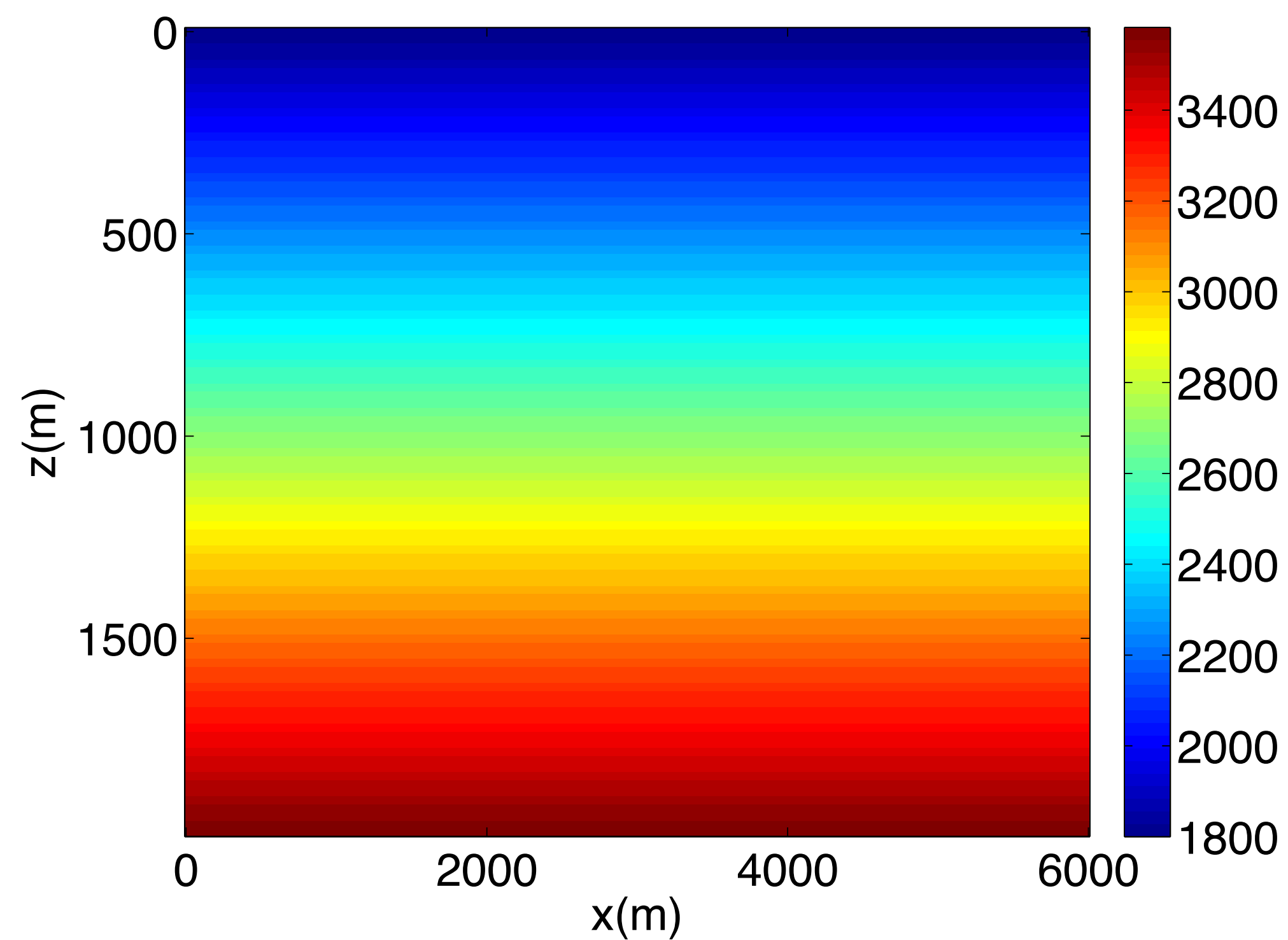
$$\begin{aligned} \|A\|_F^2 &= \text{trace}(A^T A) \\ &\approx \sum_{i=1}^K \mathbf{w}_i^T A^T A \mathbf{w}_i = \sum_{i=1}^K \|A \mathbf{w}_i\|_2^2 \end{aligned}$$

where $\sum_{i=1}^K \mathbf{w}_i \mathbf{w}_i^T \approx I$

Randomized probing [reflection]

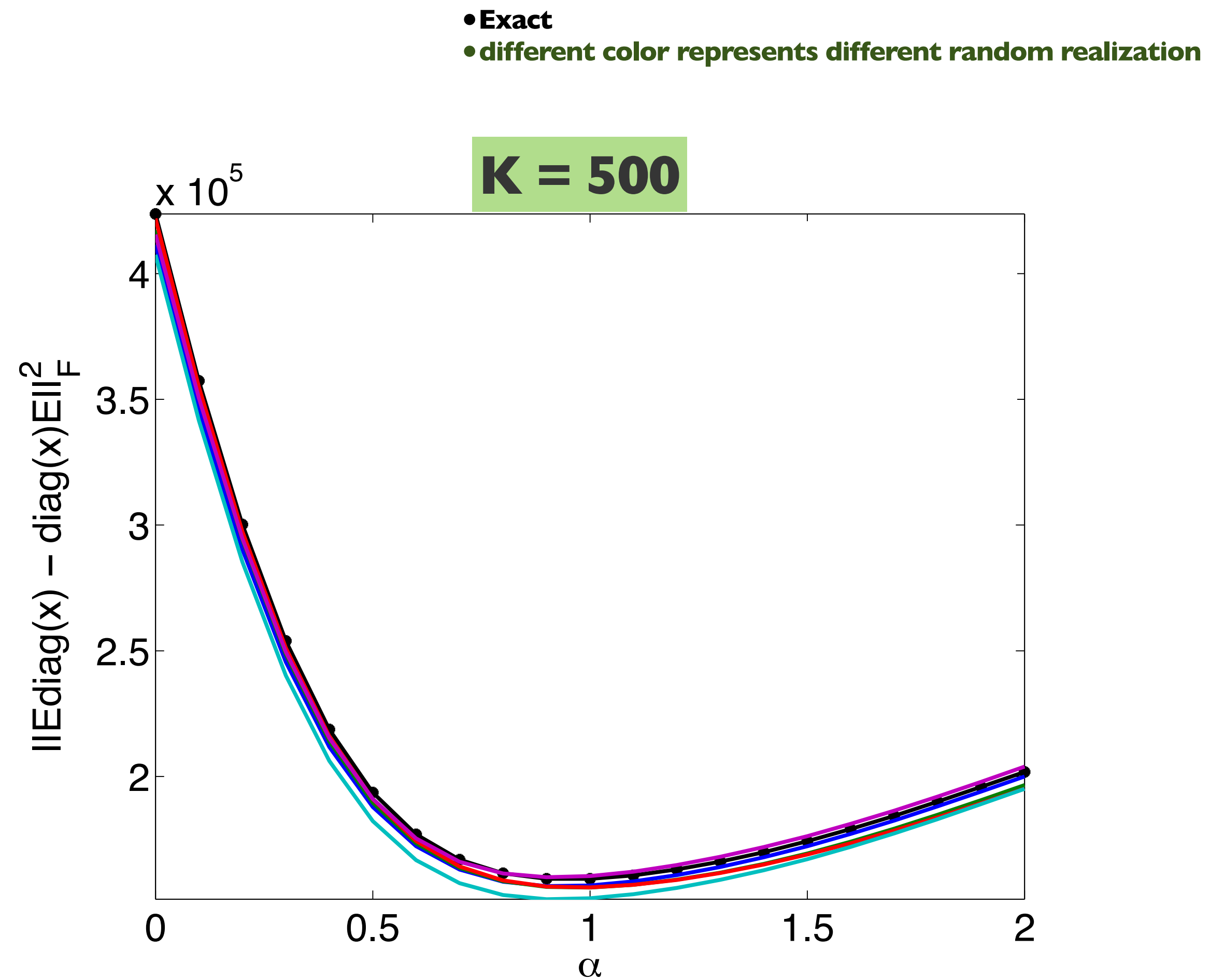
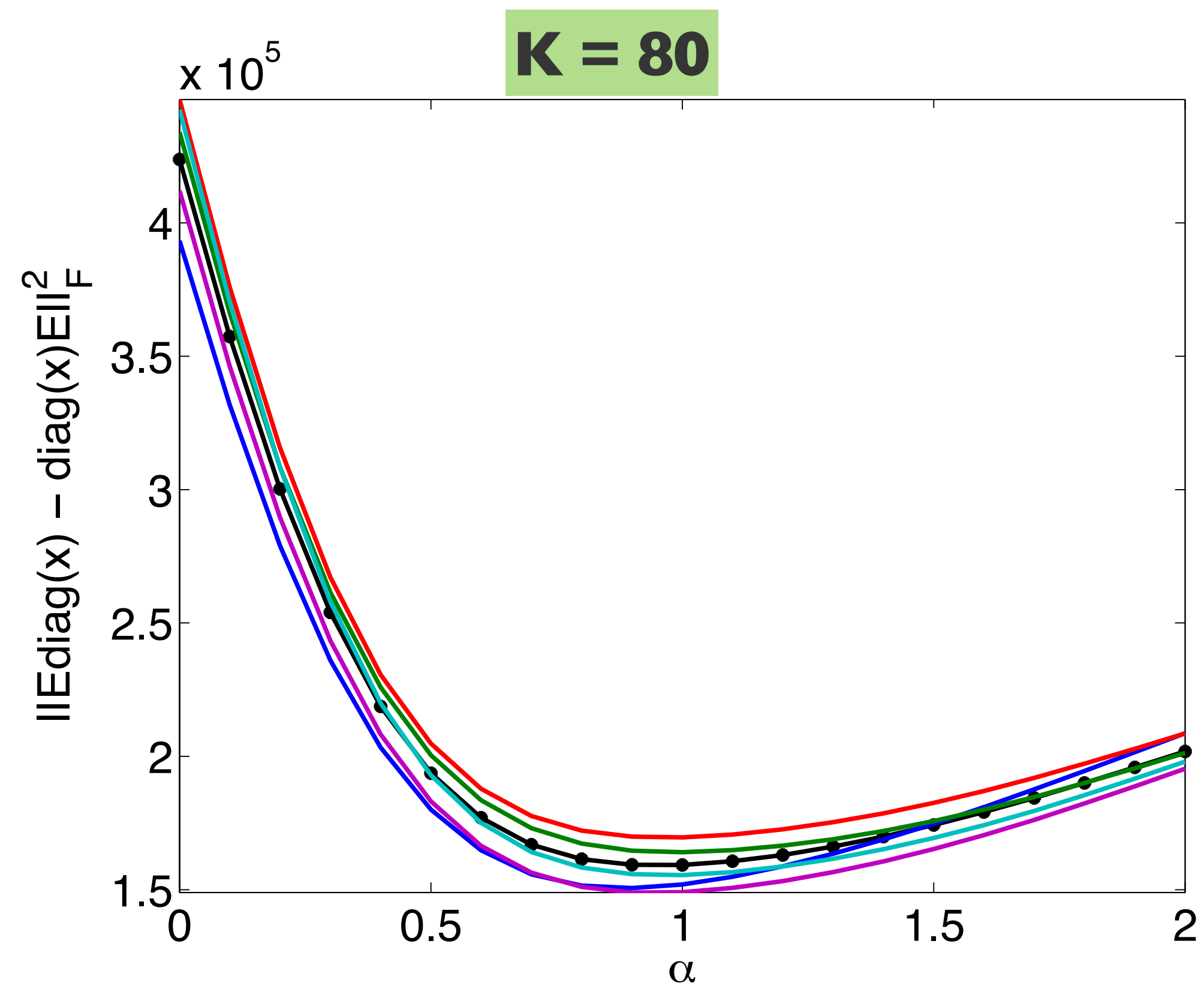


true model



initial model

Randomized probing [reflection]

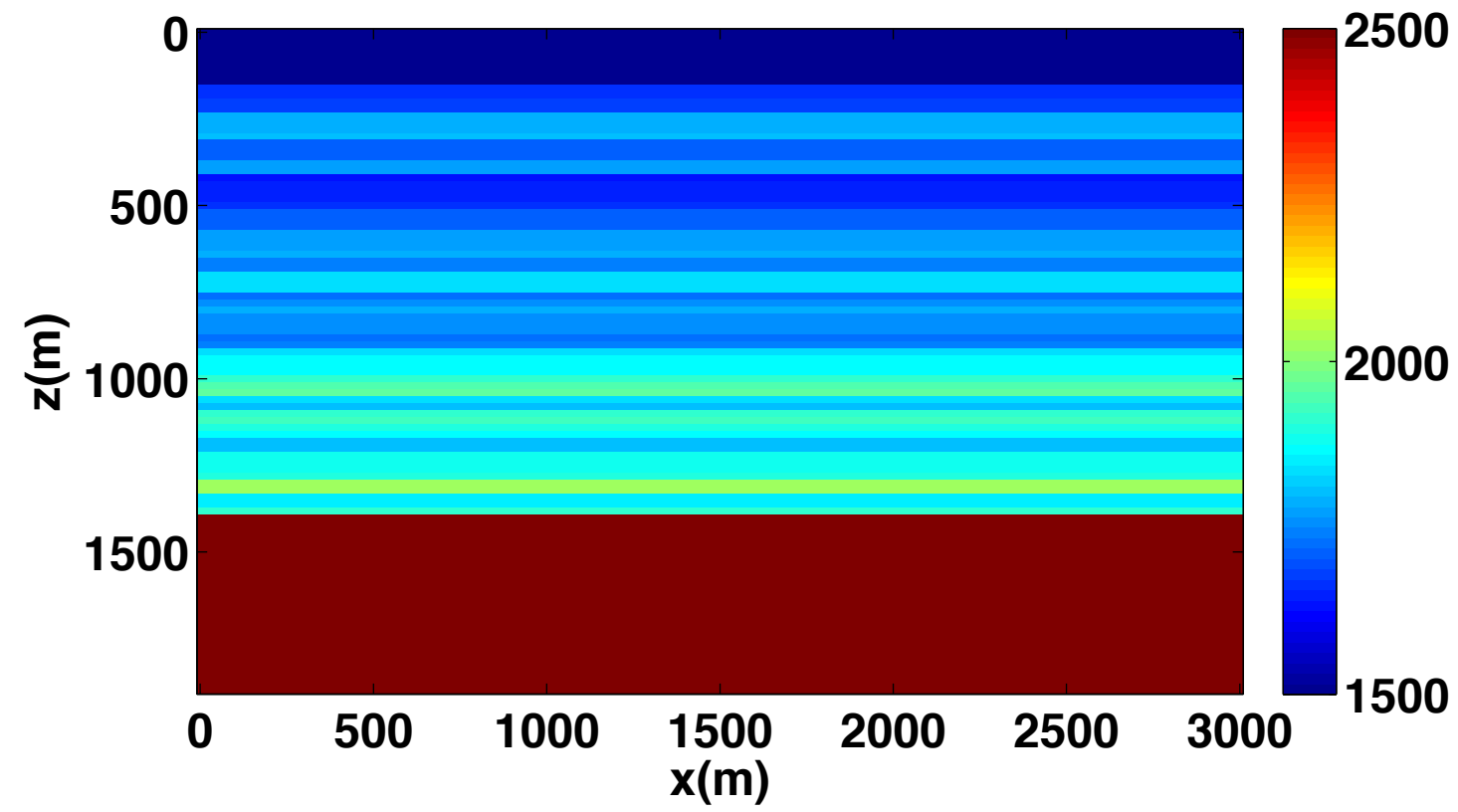


Applications

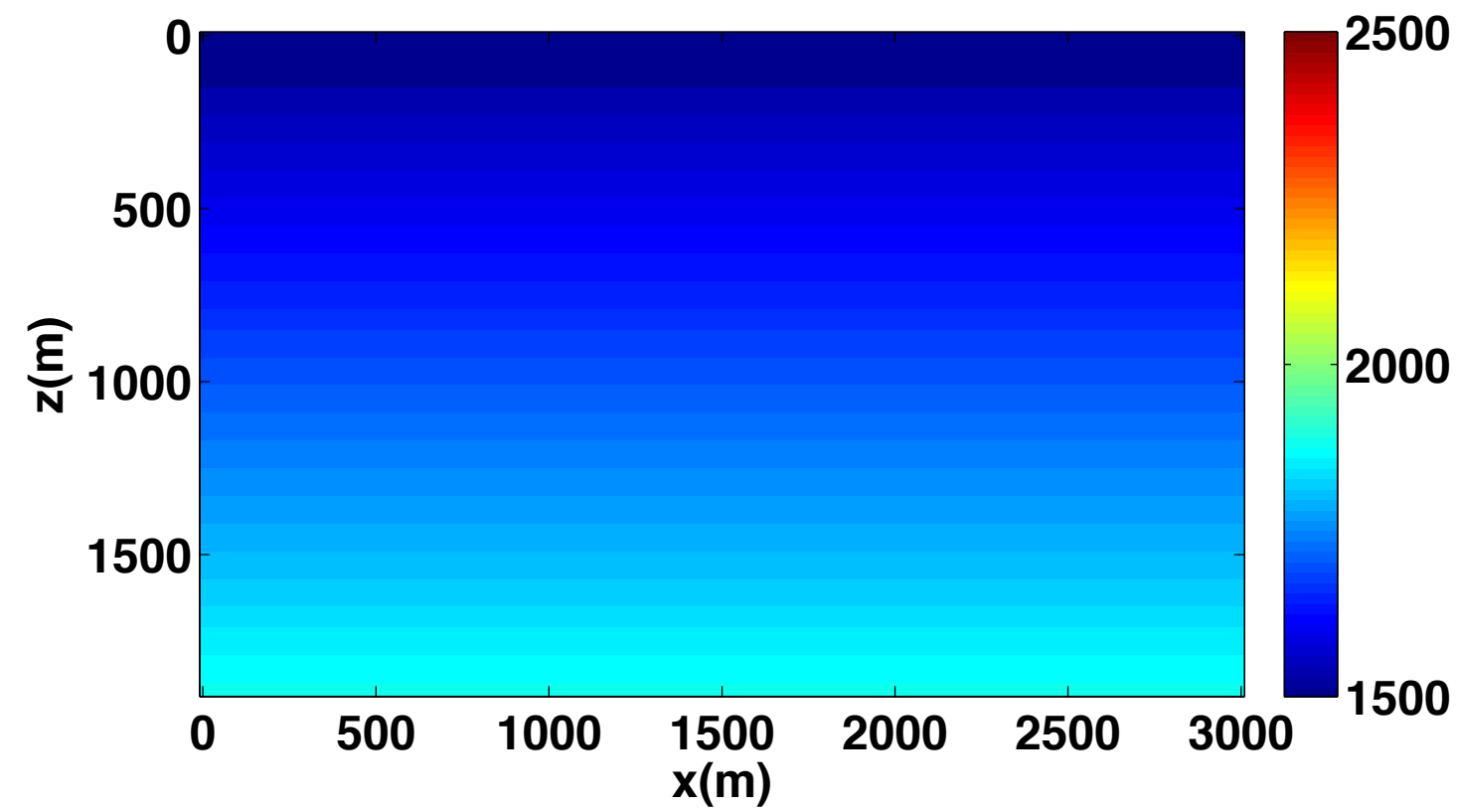
- Reflector model
- Lens model
- Vertical gradient model
- Marmousi model

Reflector model

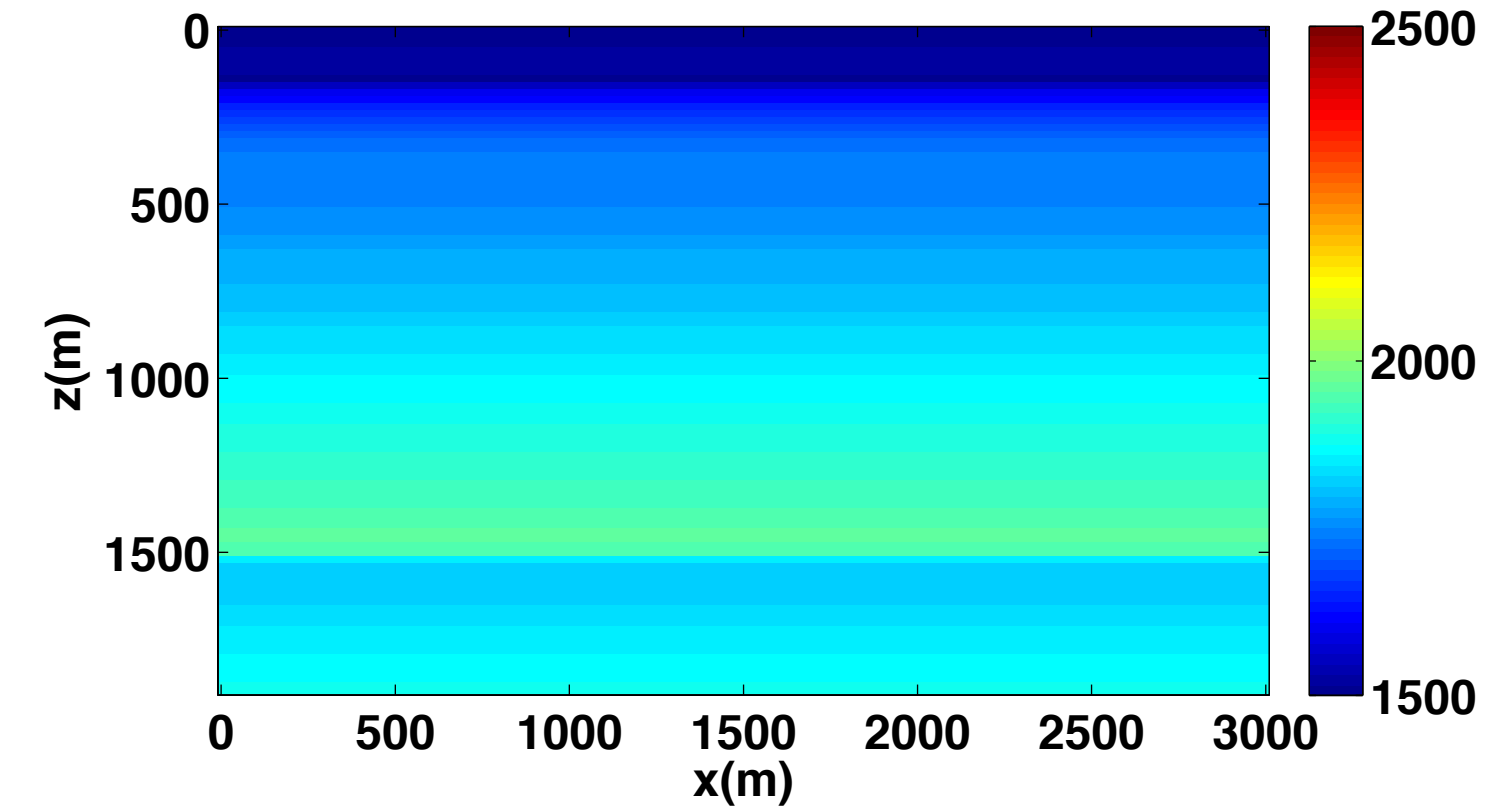
True Model



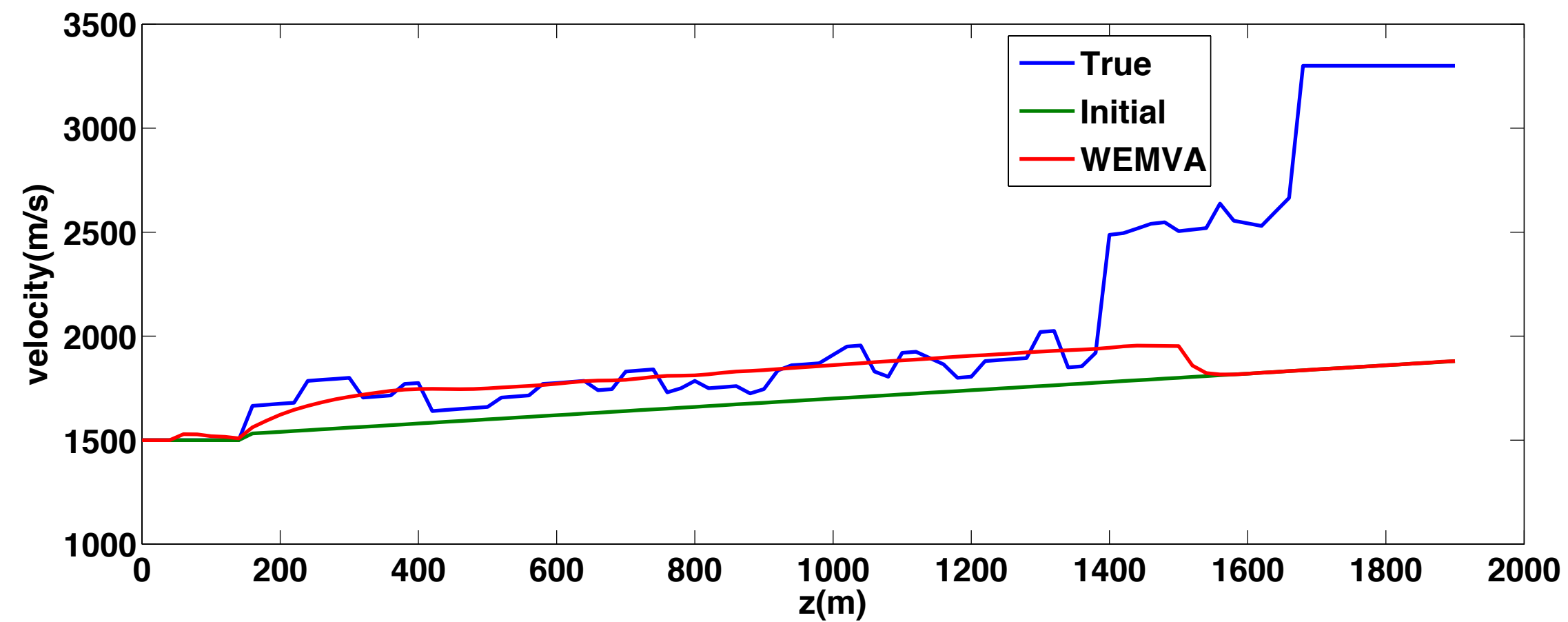
Initial Model



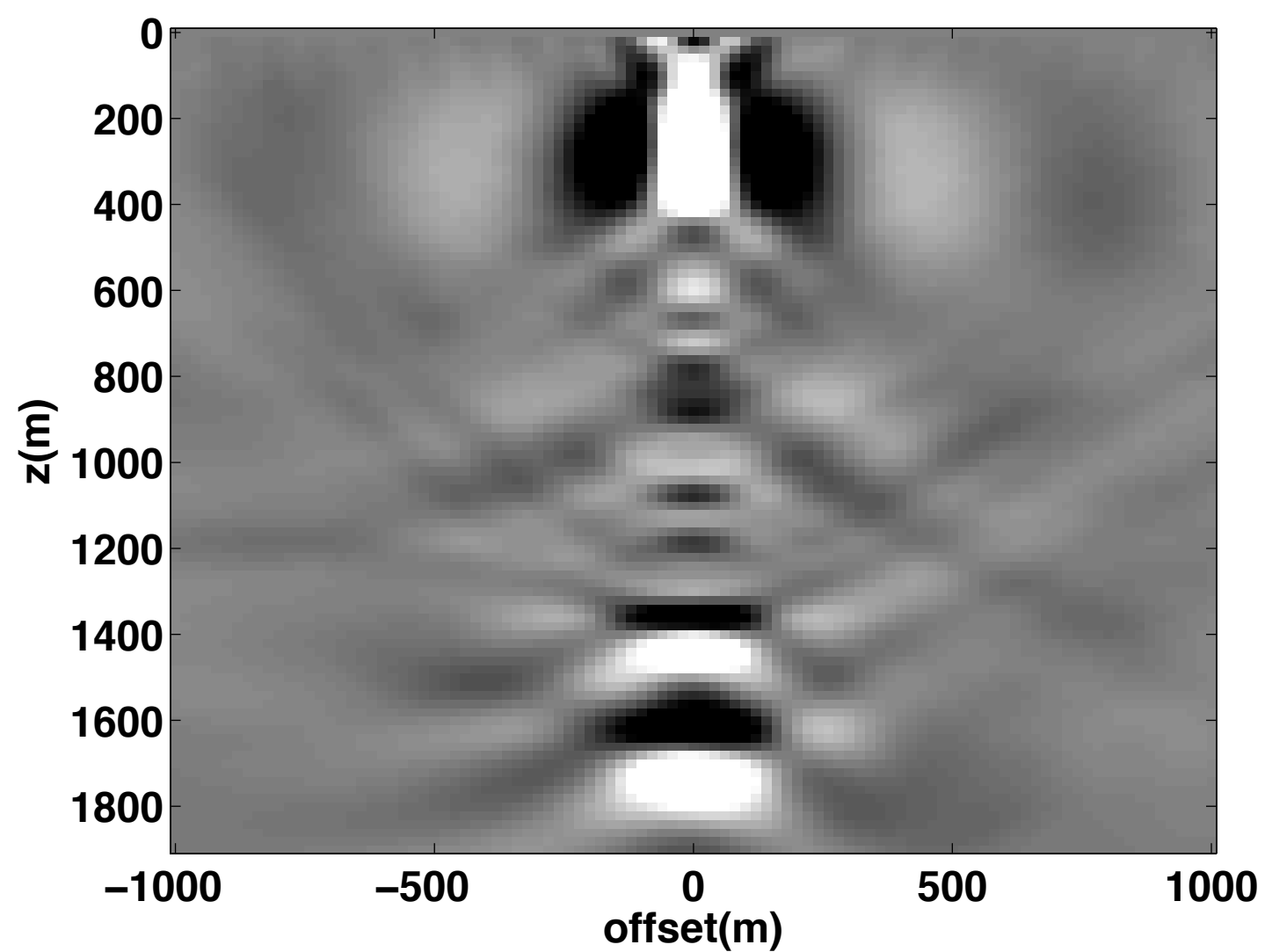
WEMVA



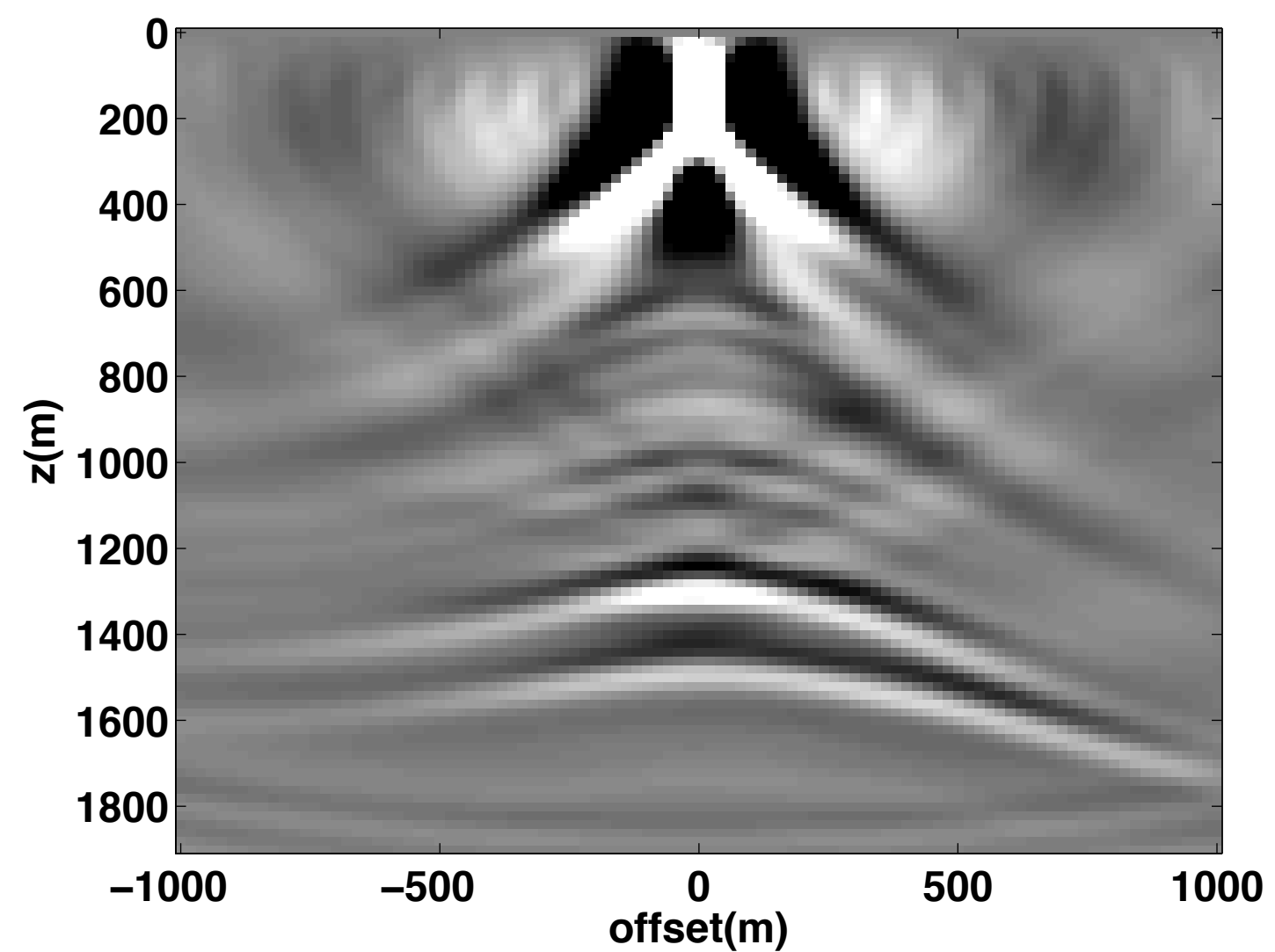
Vertical Trace



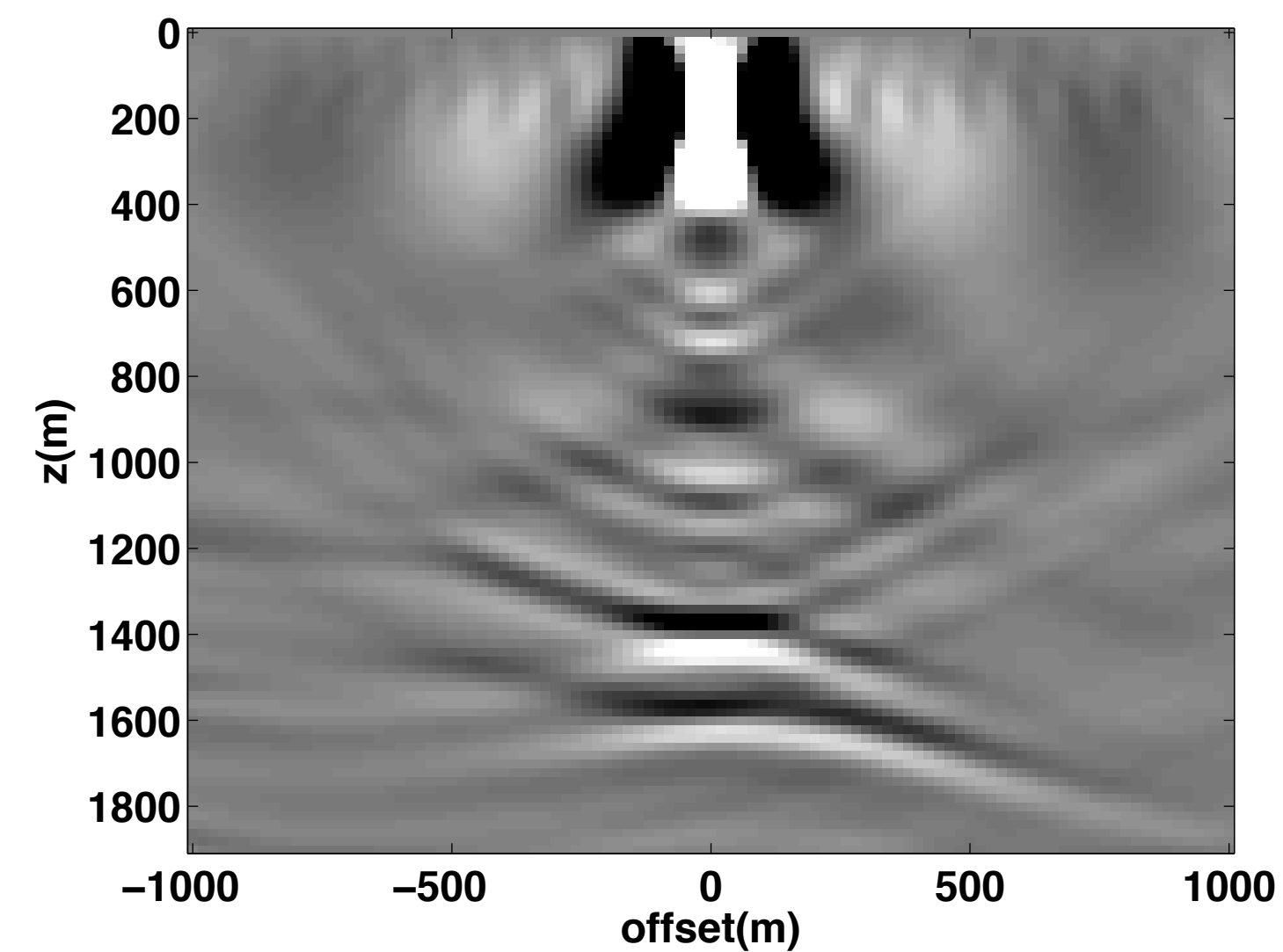
Reflector model [image gathers]



true model



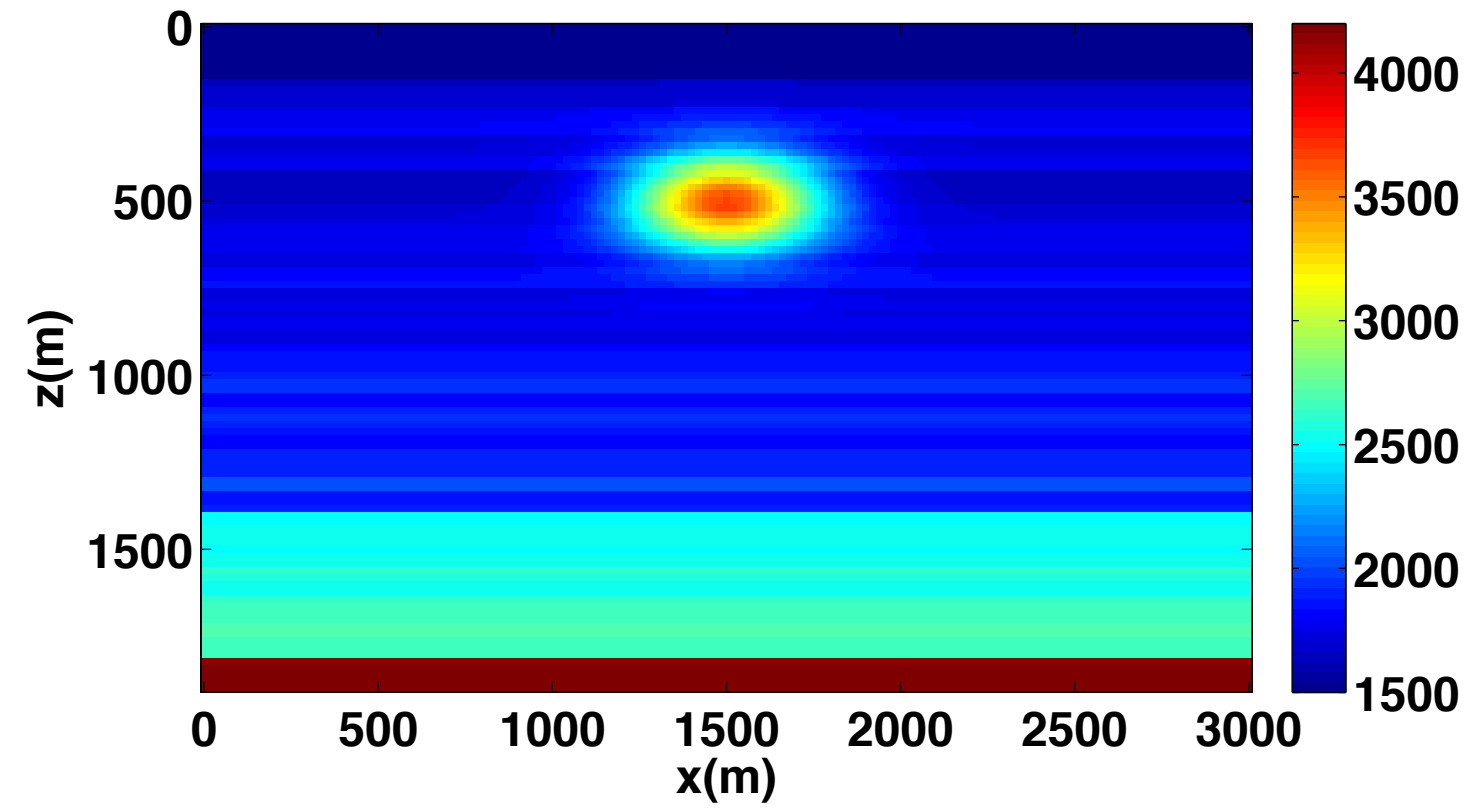
initial model



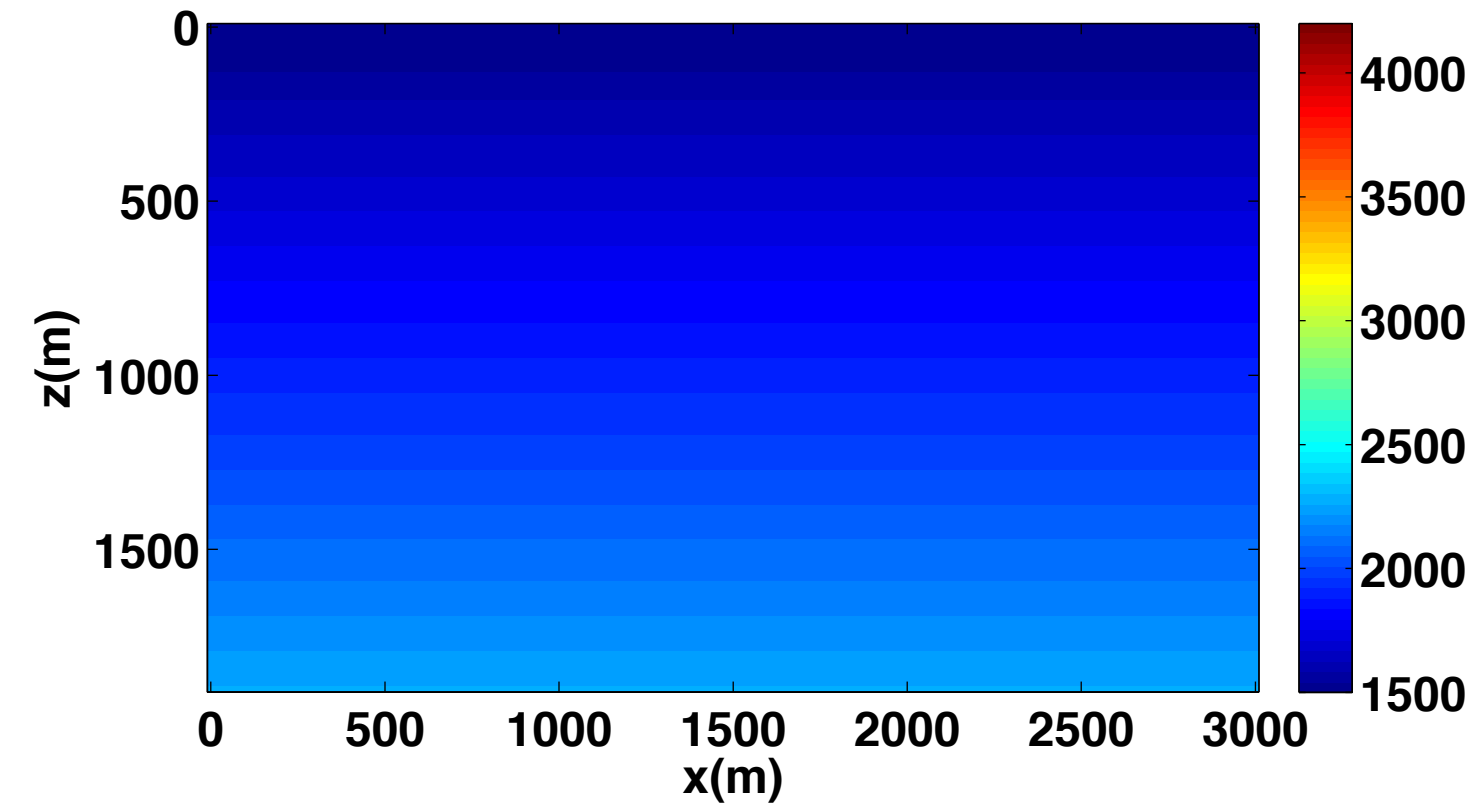
WEMVA

Lens Model

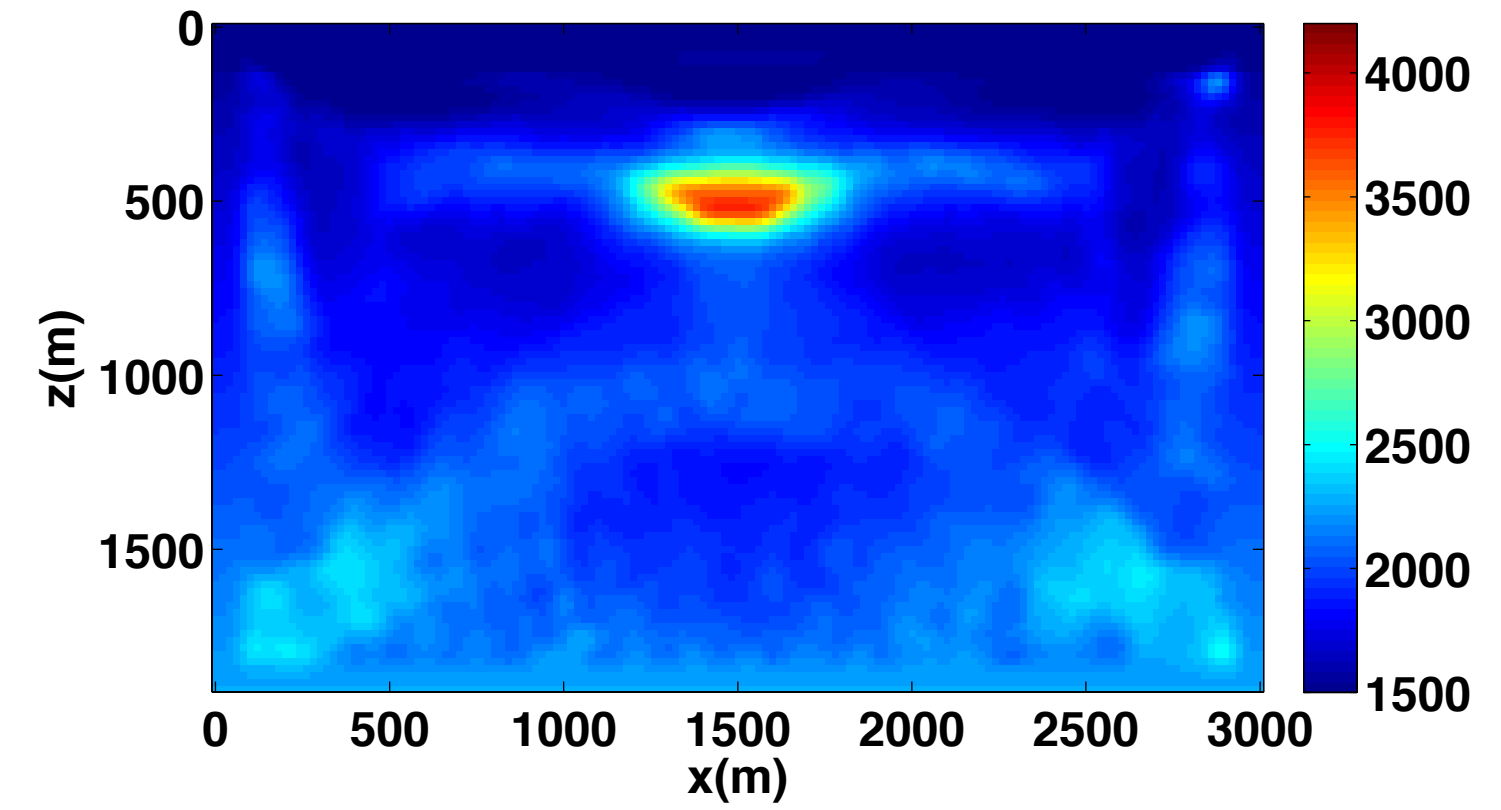
True Model



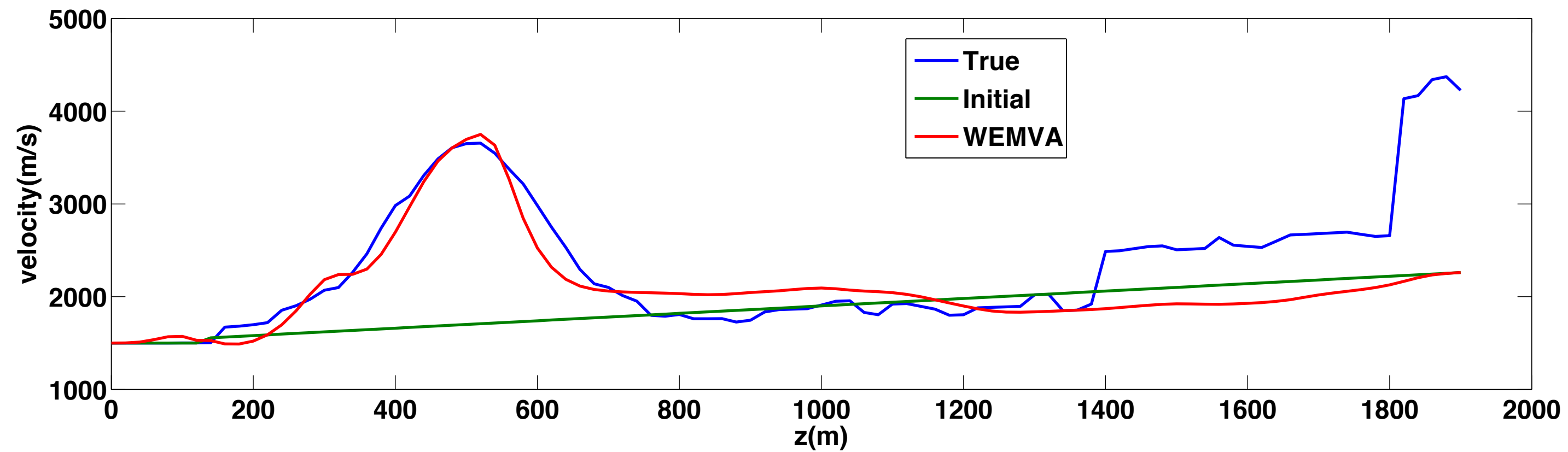
Initial Model



WEMVA

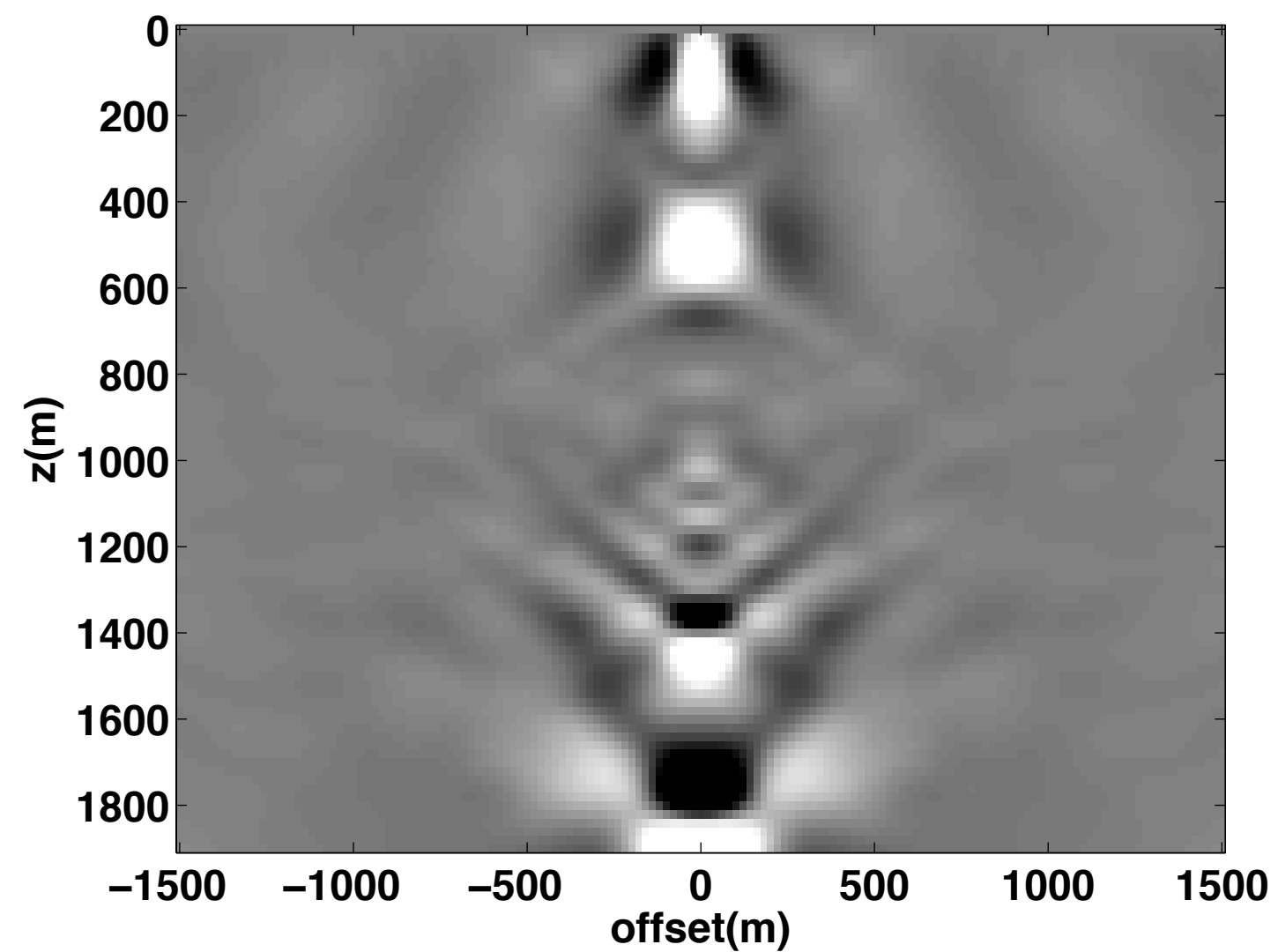


Vertical Trace

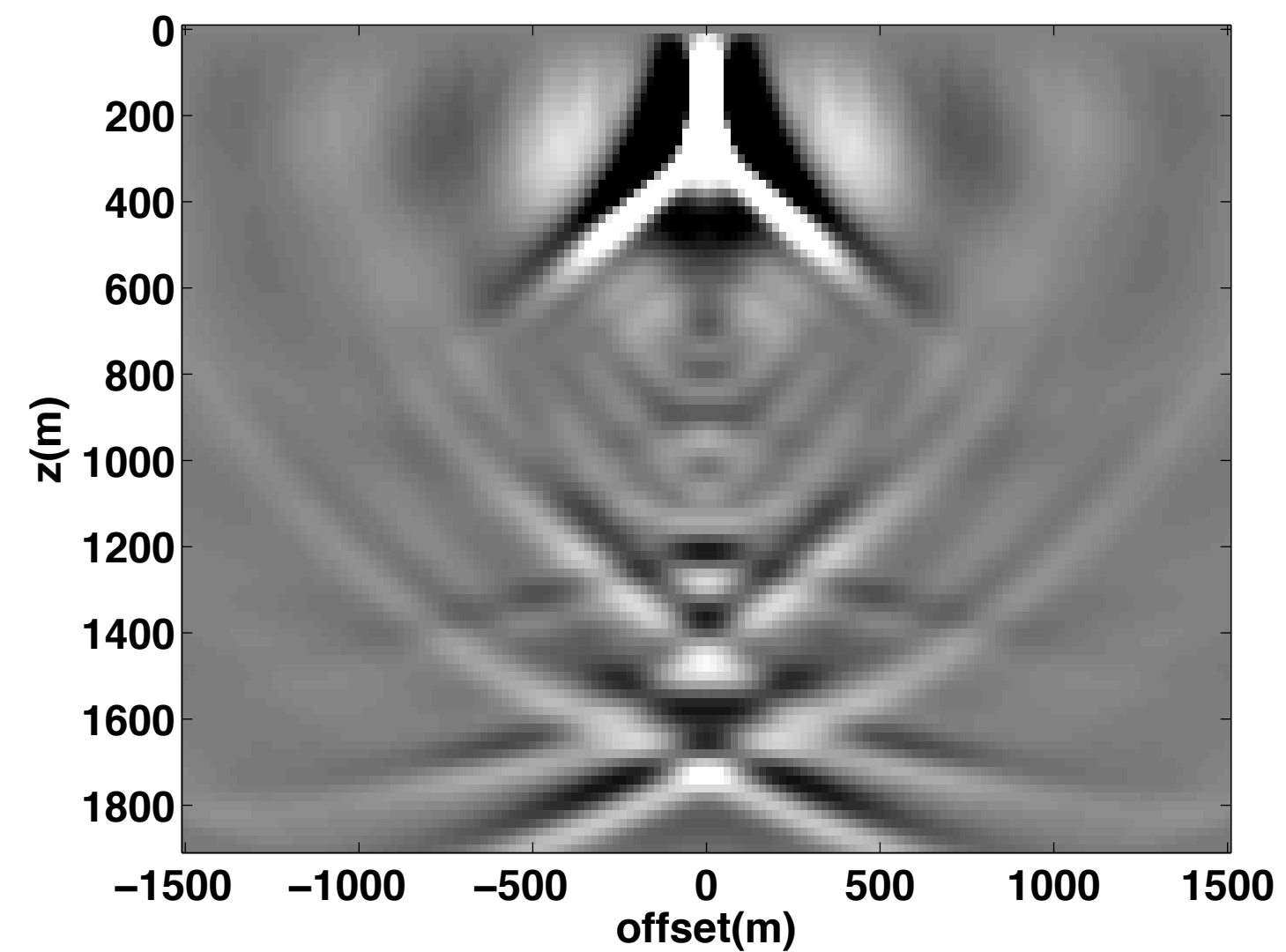


Lens Model

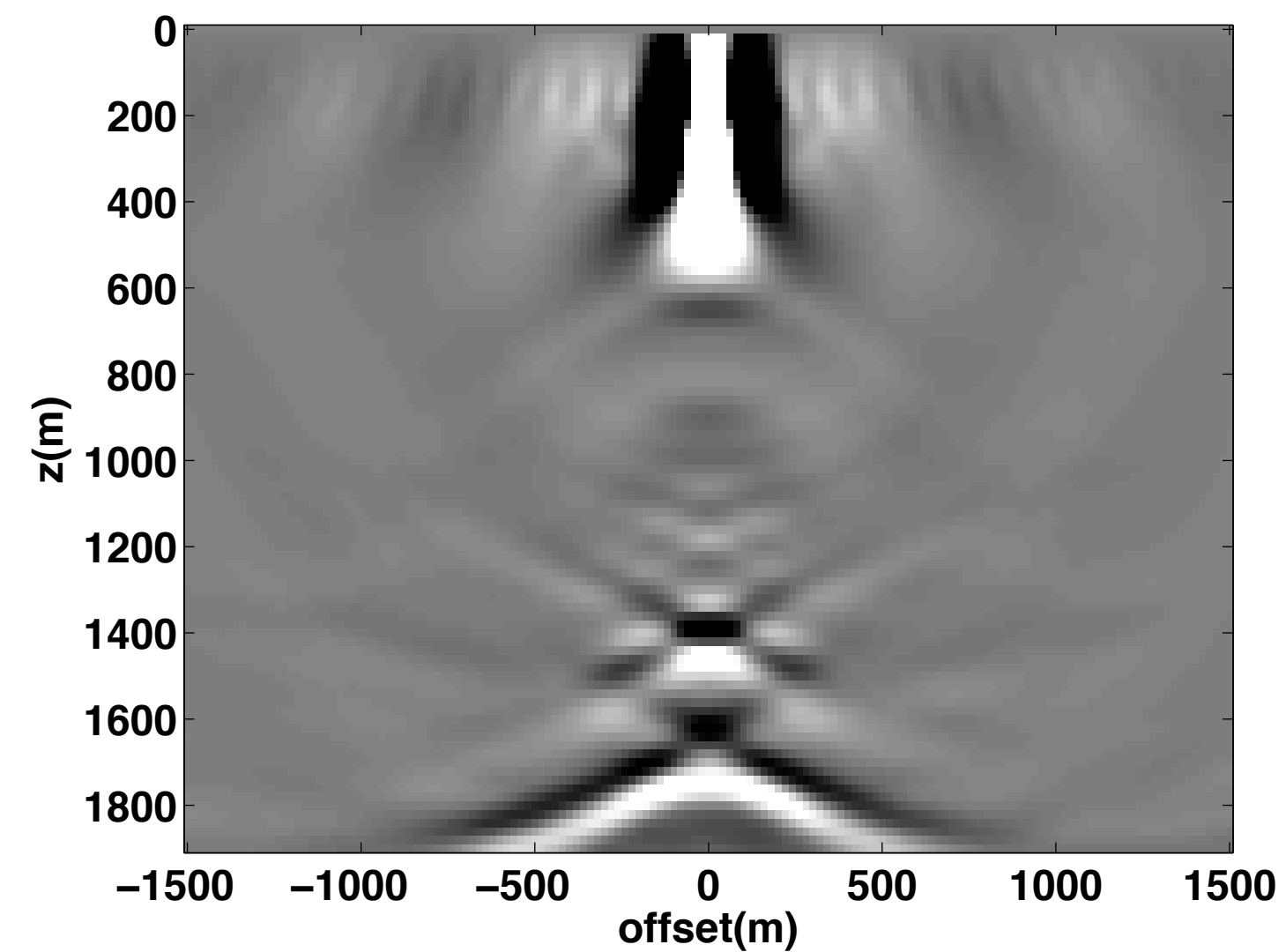
[image gathers]



true model

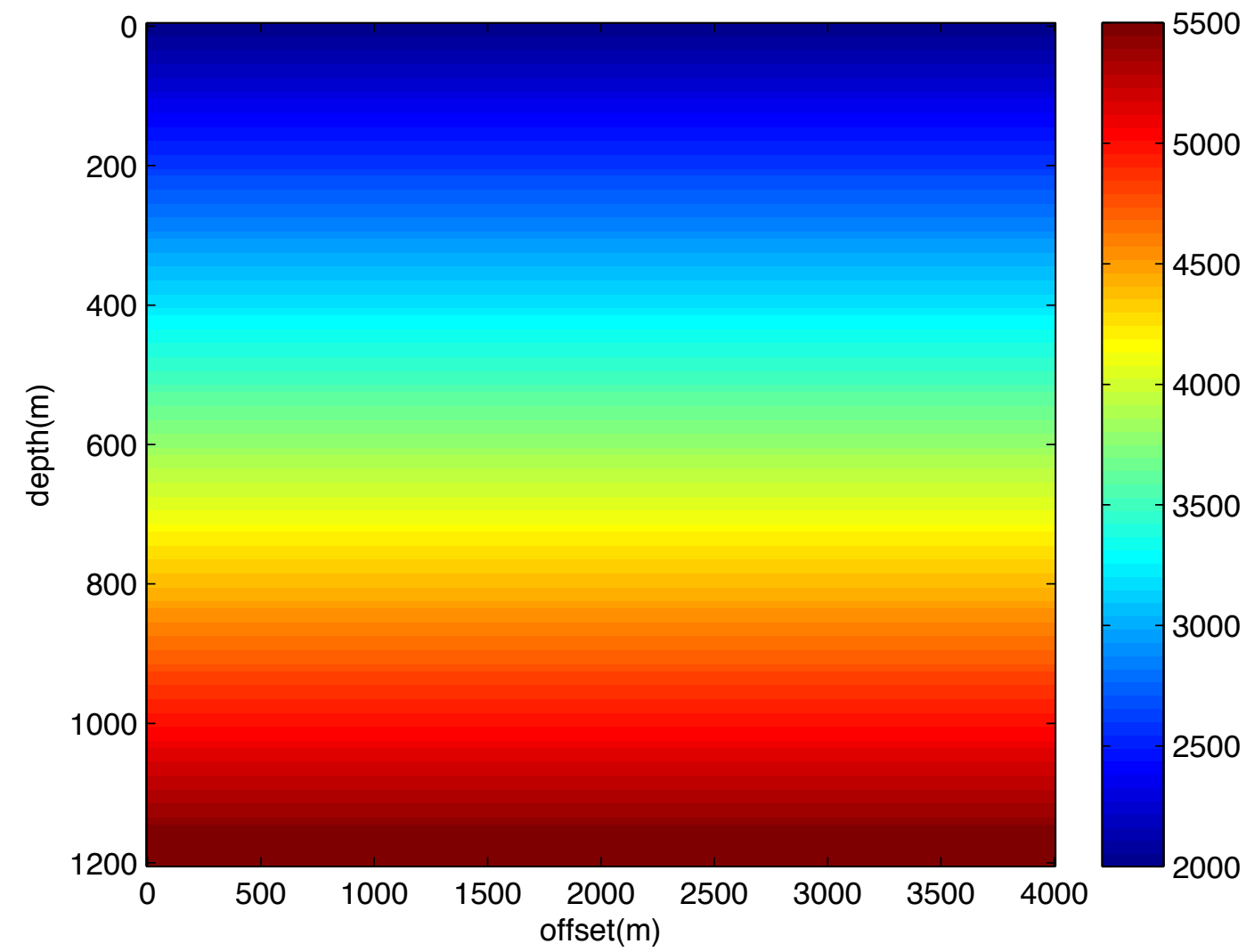


initial model

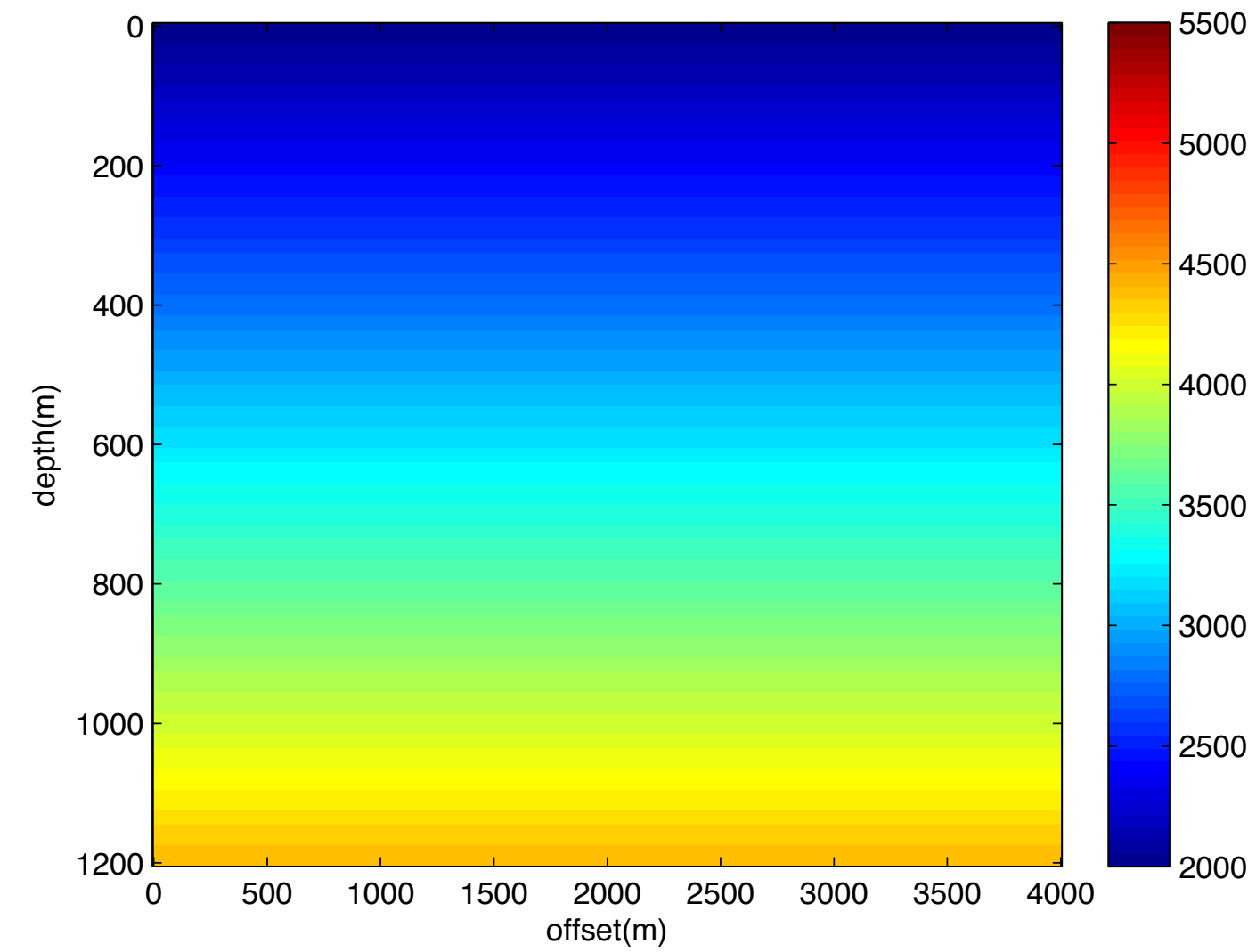


WEMVA

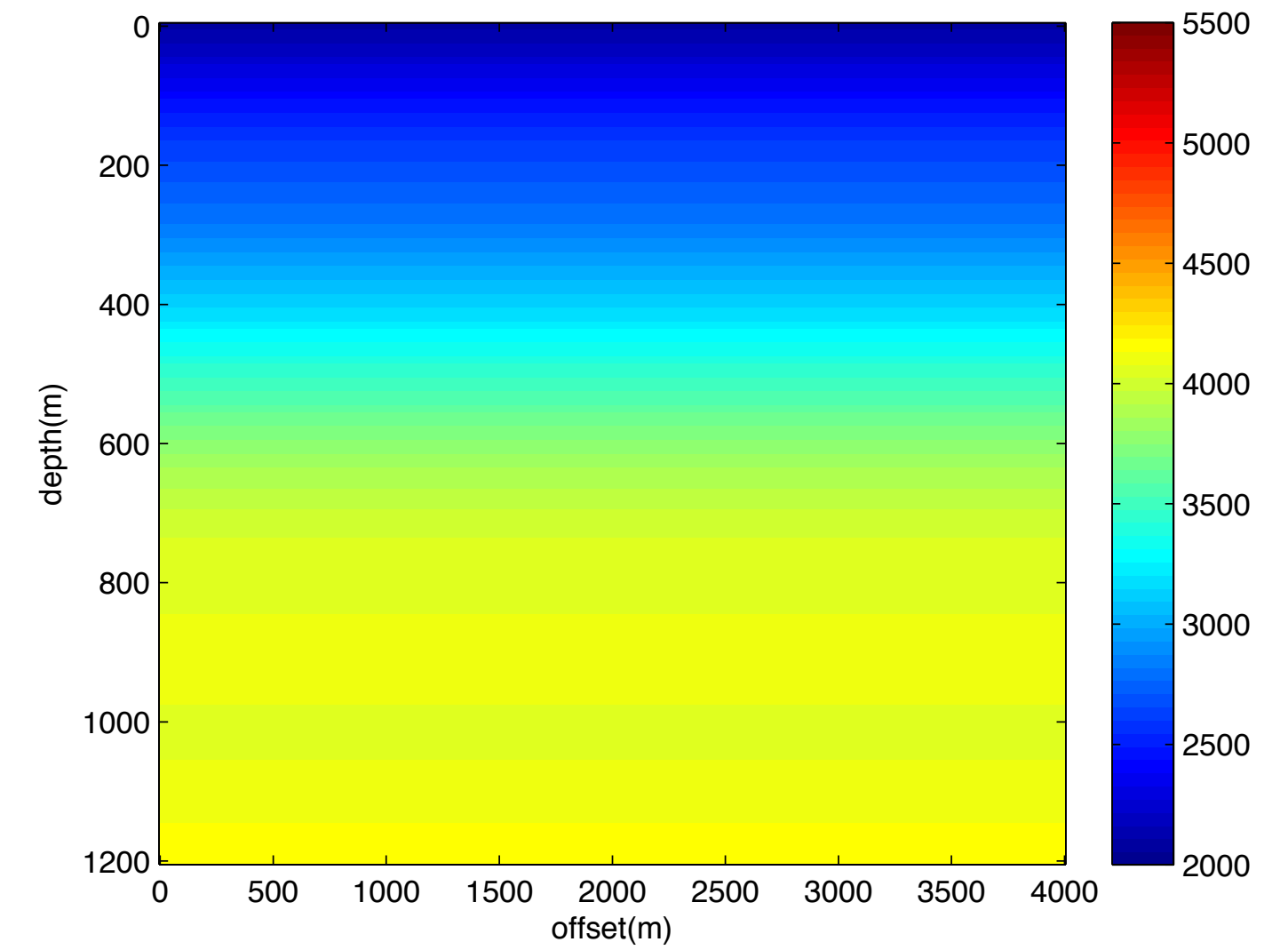
Vertical gradient [diving waves]



true model

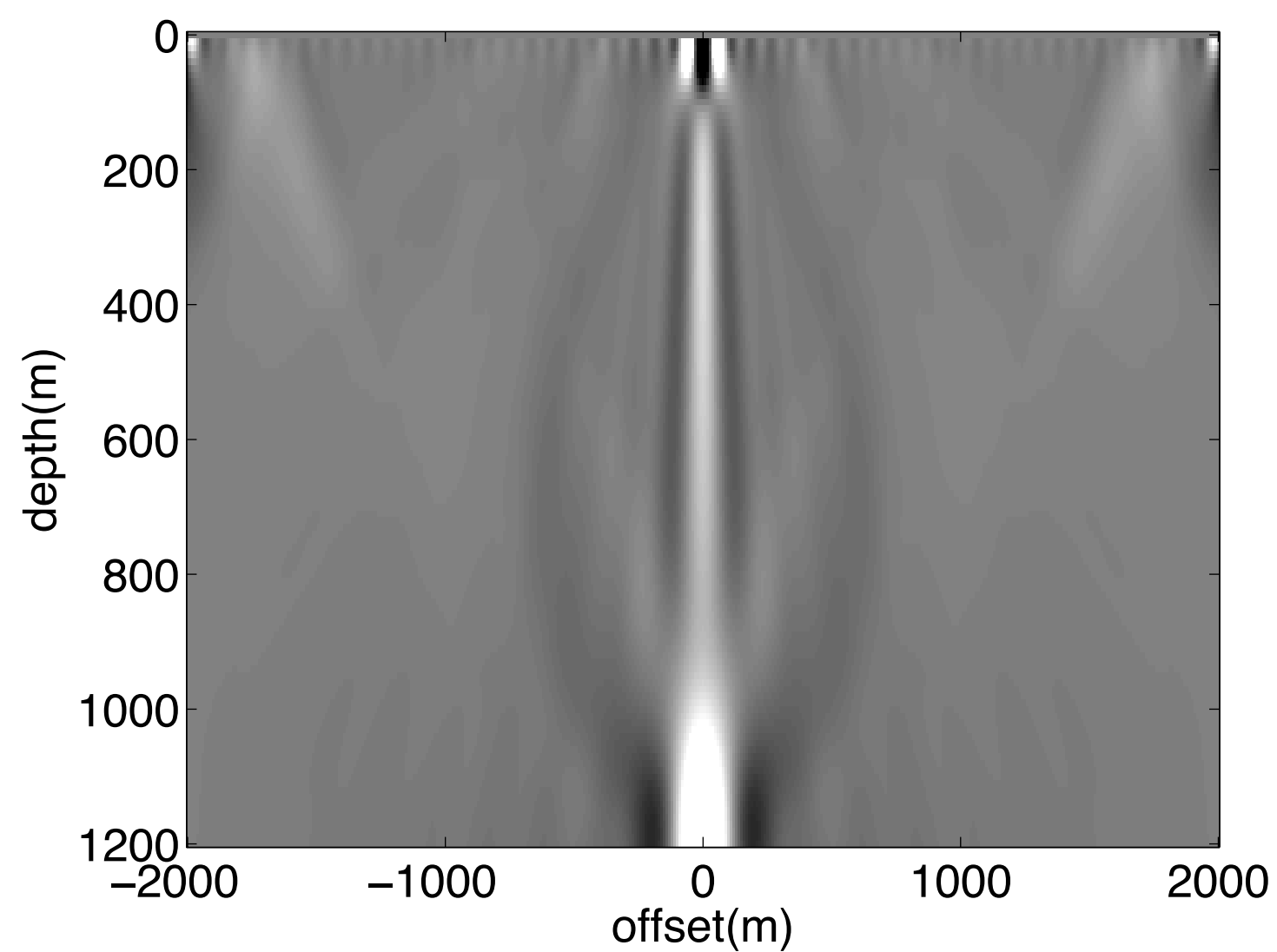


initial model

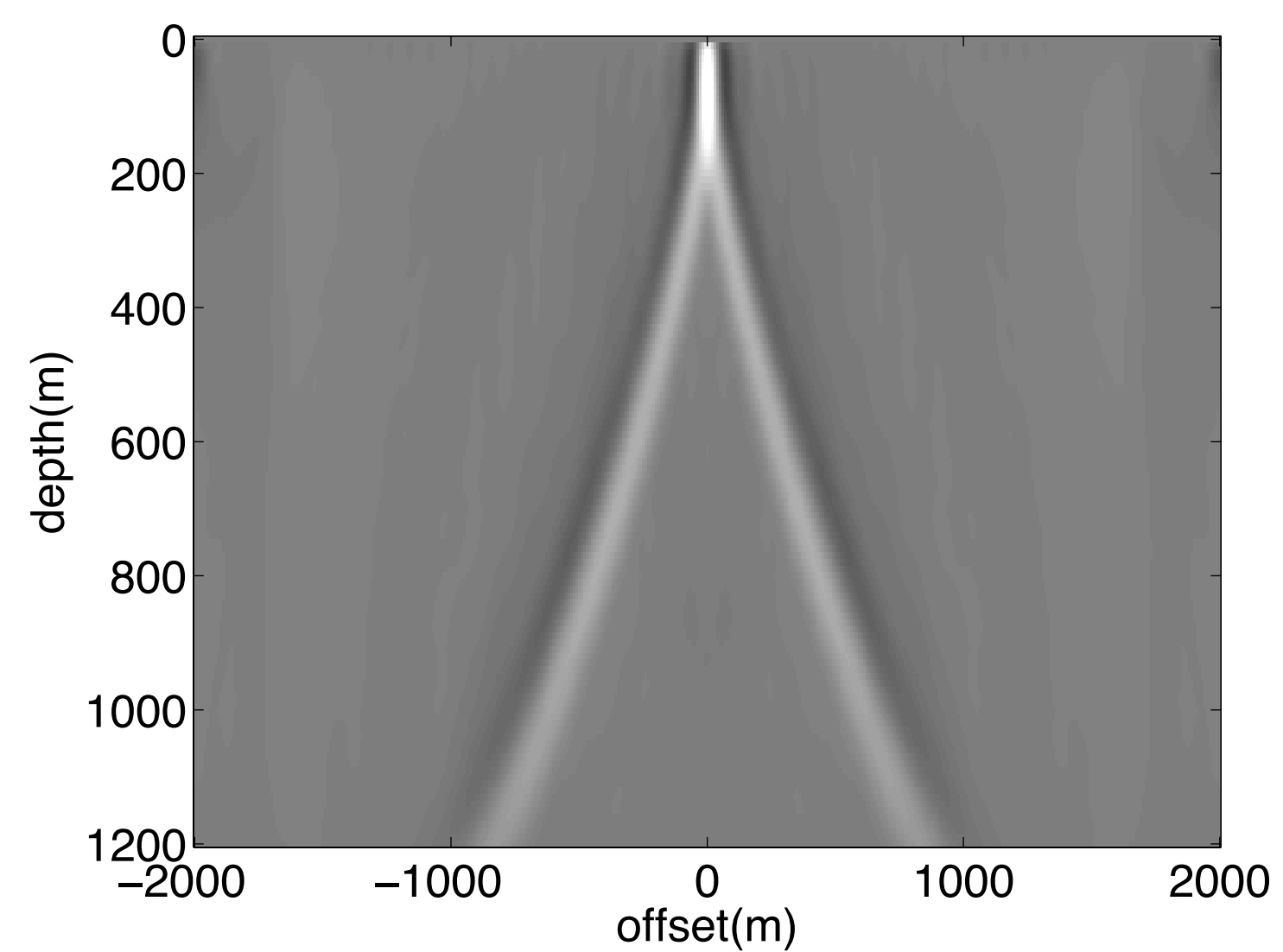


WEMVA

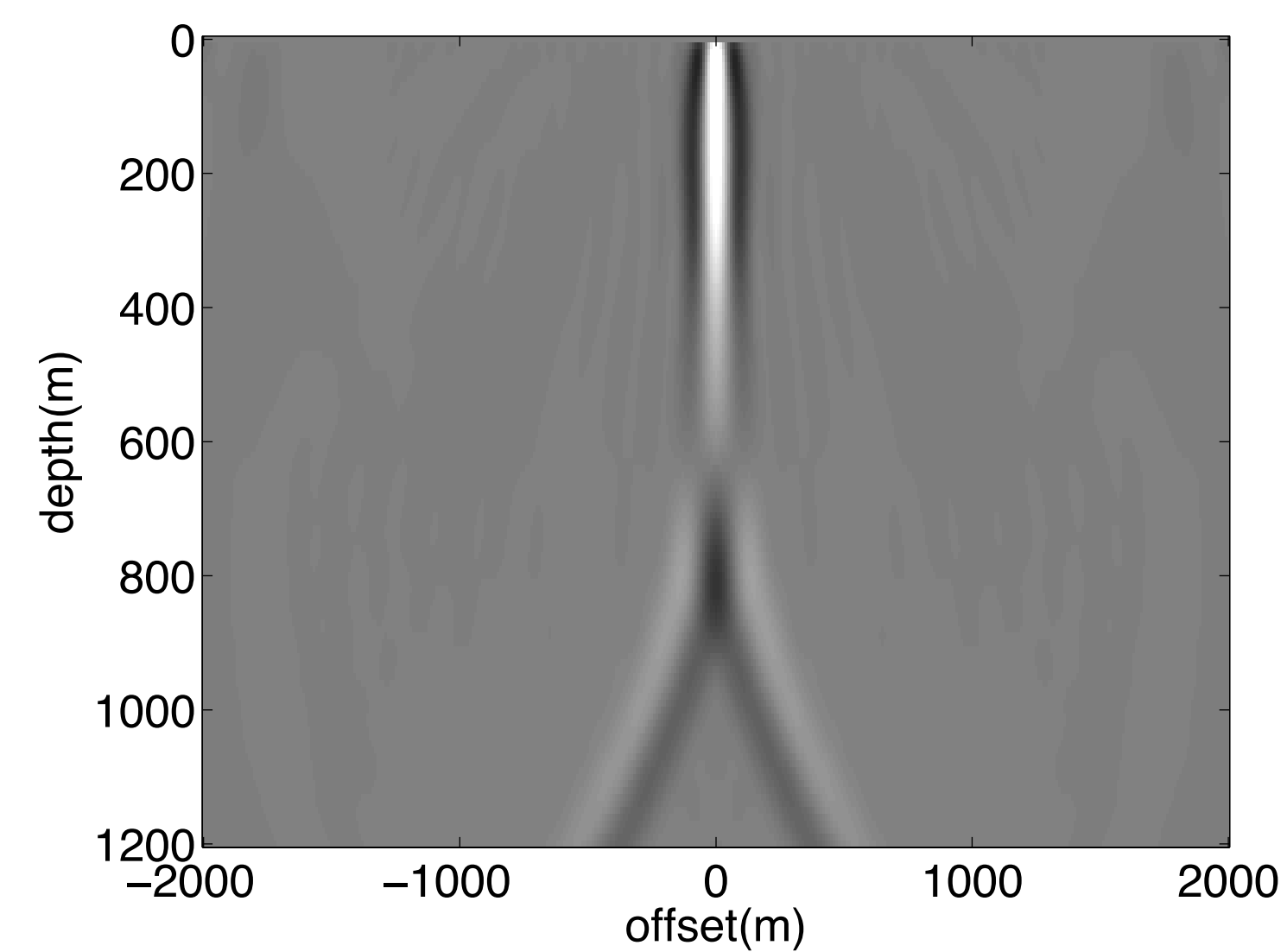
Vertical gradient [image gathers]



true model



initial model

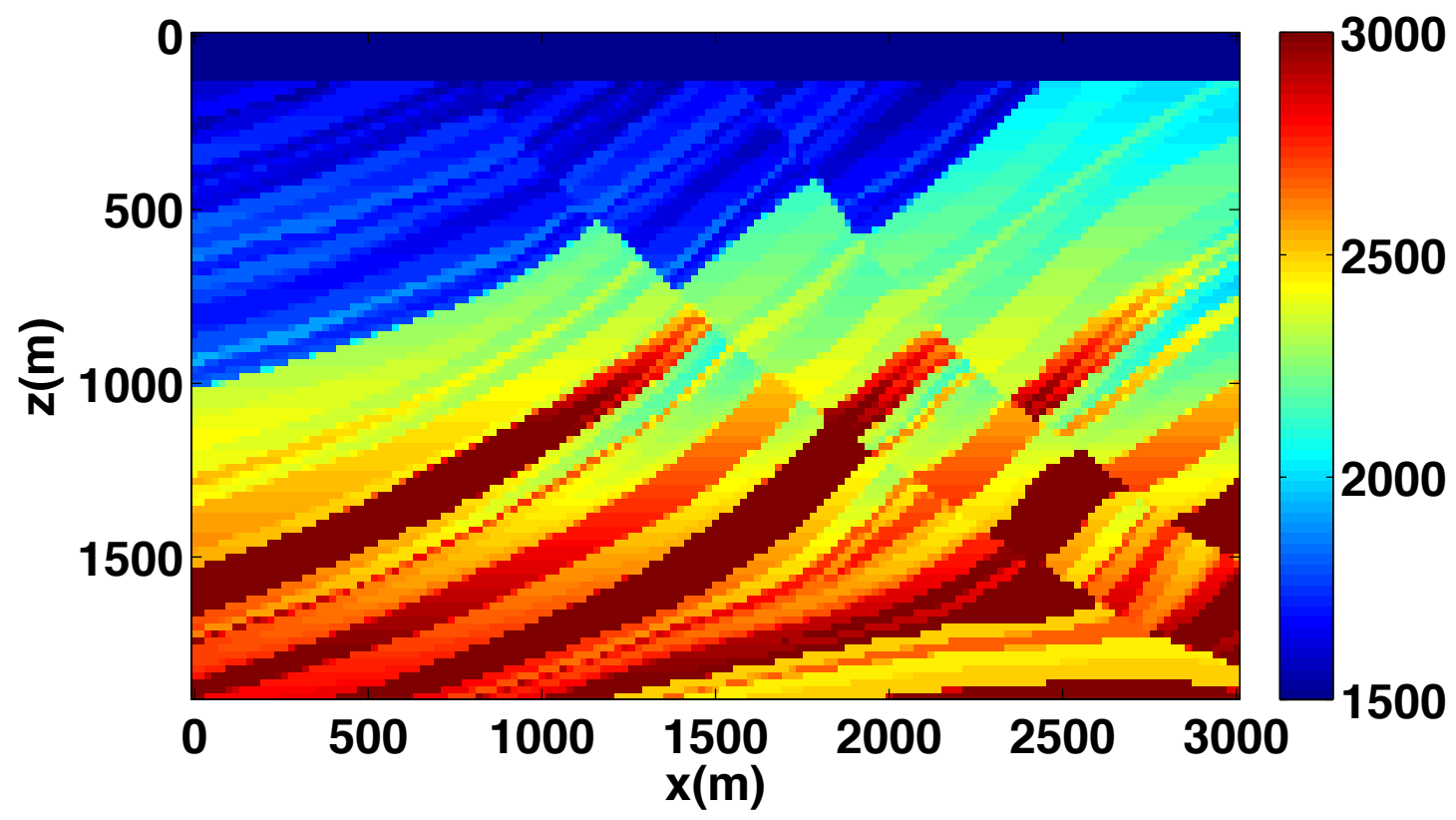


WEMVA

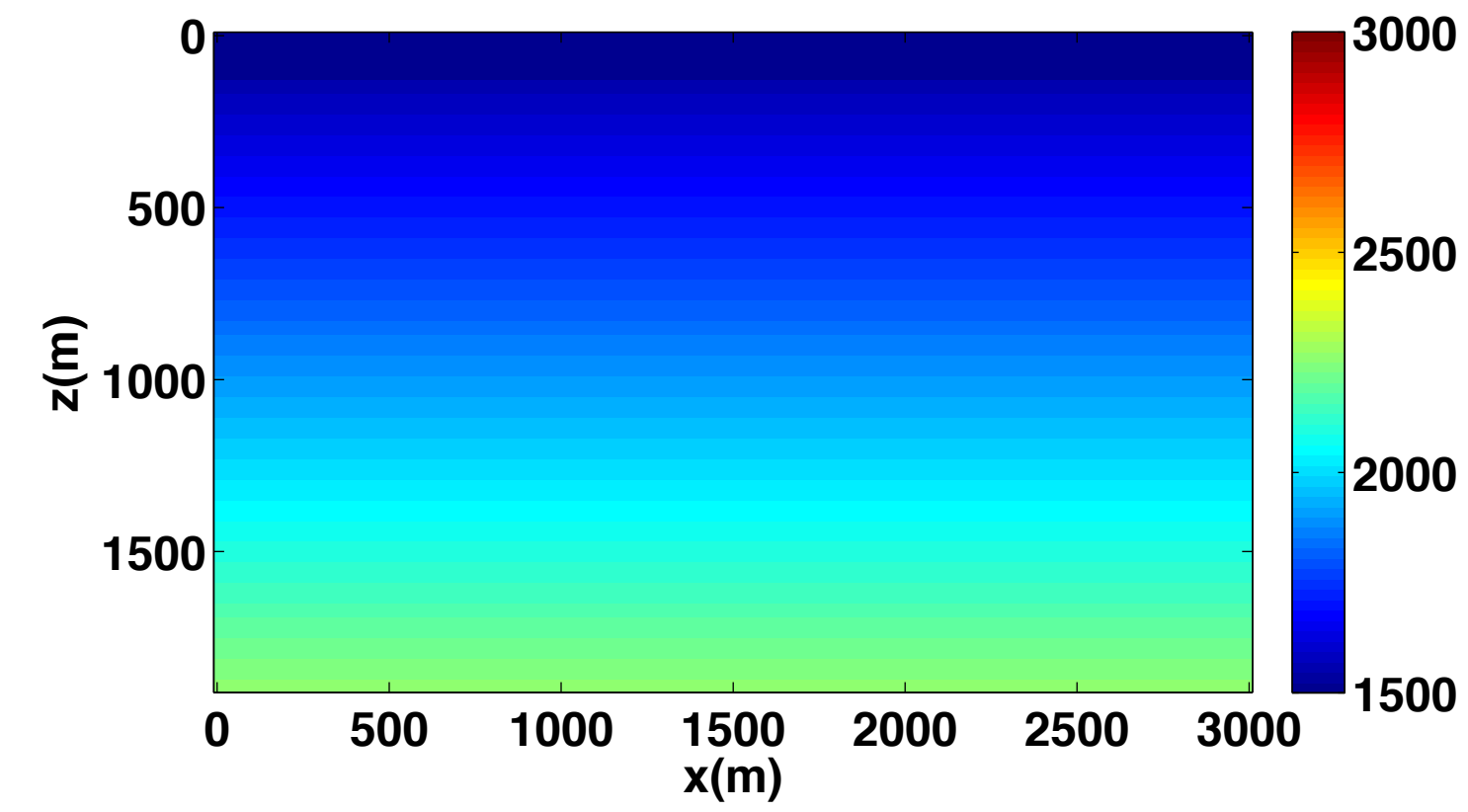
Marmousi Model

[preliminary results]

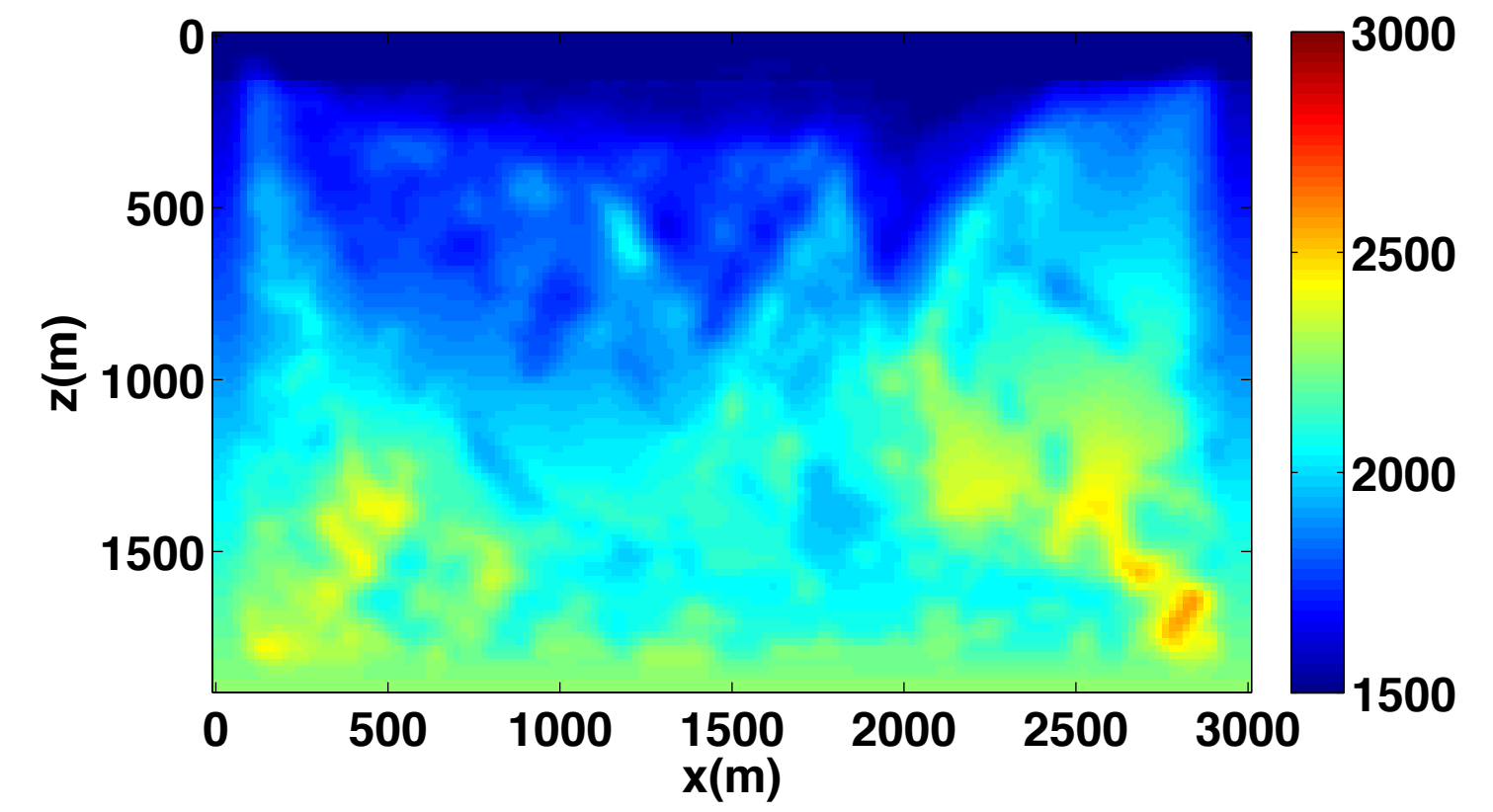
True Model



Initial Model



WEMVA



Conclusions

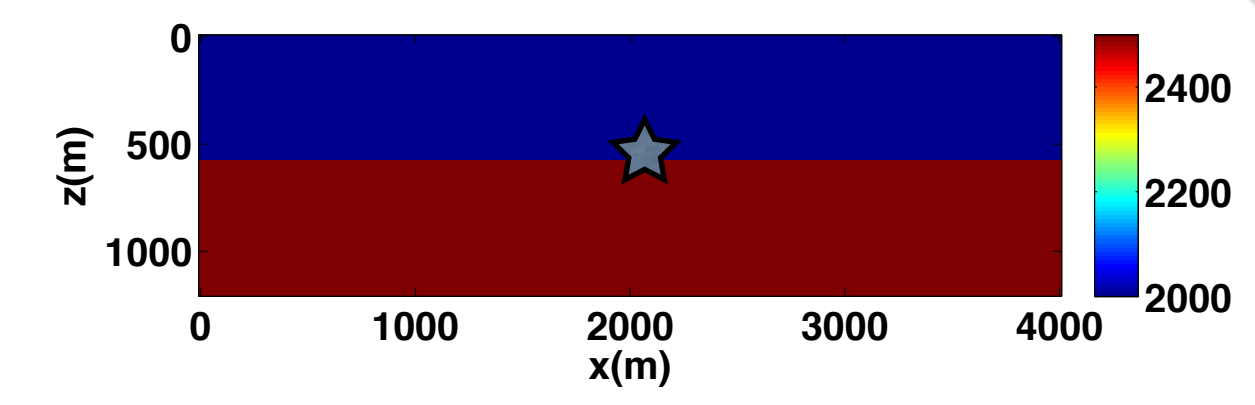
- *probing* allows us to get *offset* information for *all direction*
- *randomized* trace estimation allows us to *compute WEMVA* objective cheaply

Future Work

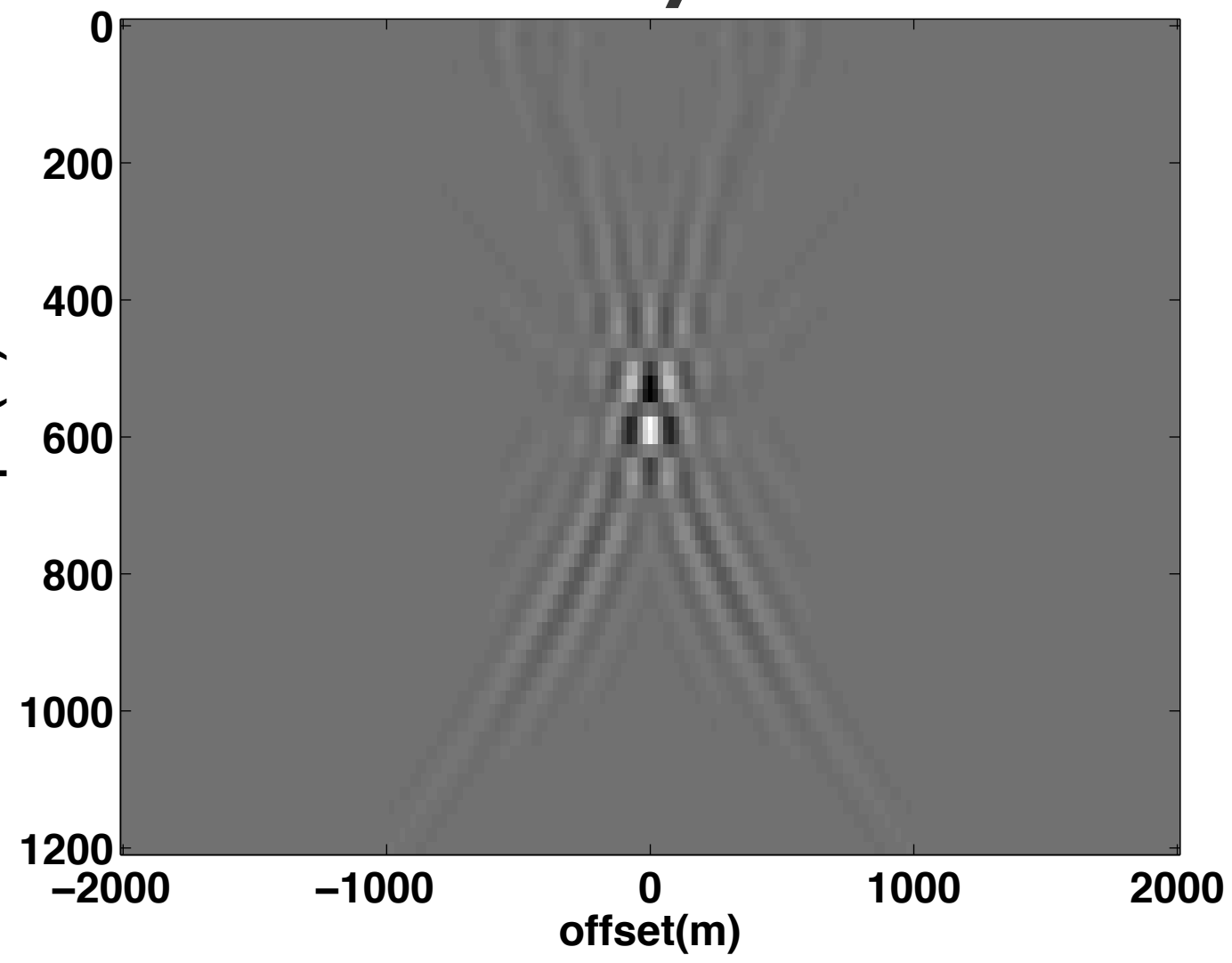
- control *sloppiness* in WEMVA (*frugal method*)
- incorporate the *free-surface multiple* in WEMVA

least-squares extended images

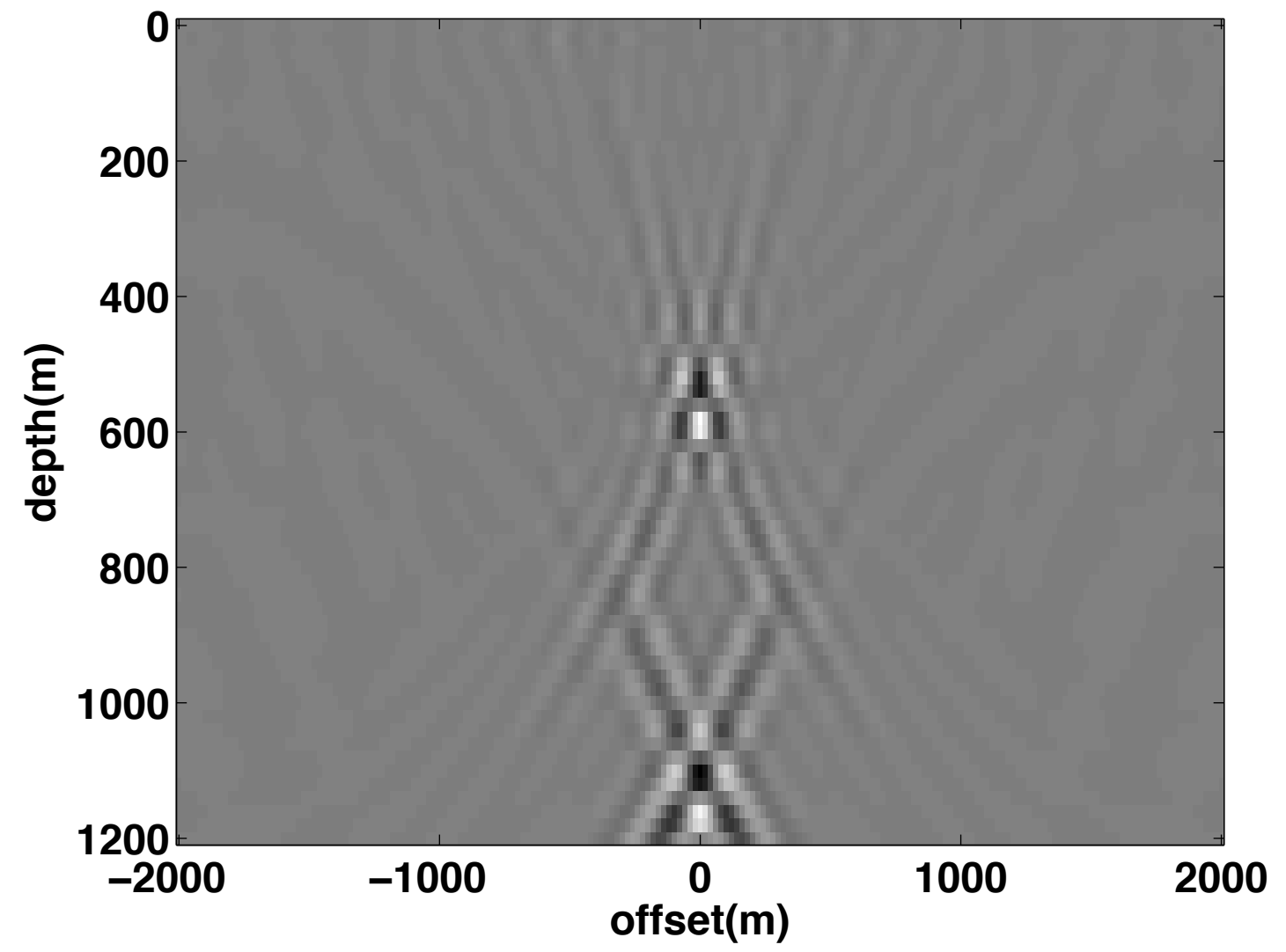
with free-surface multiples



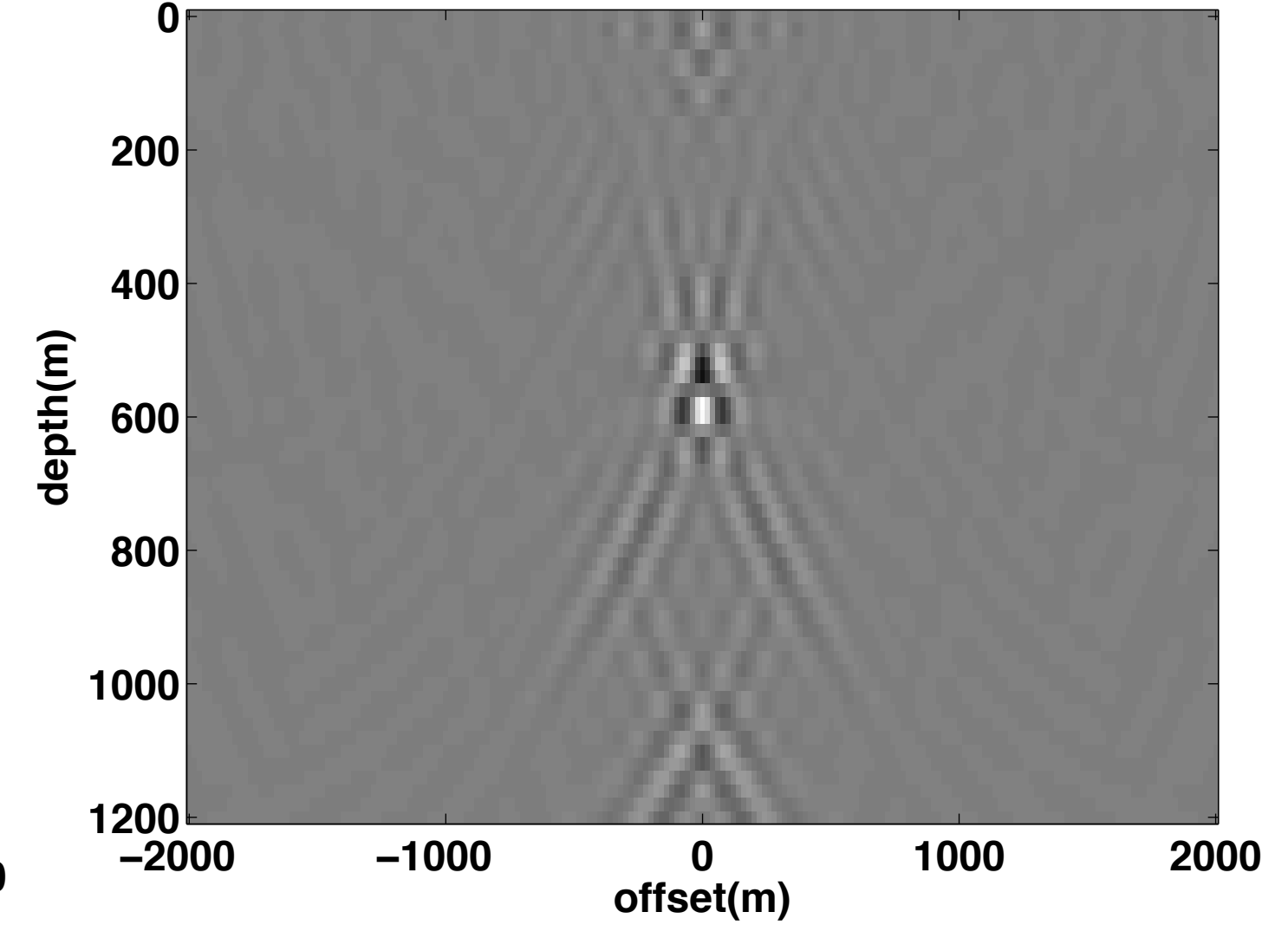
Primary data



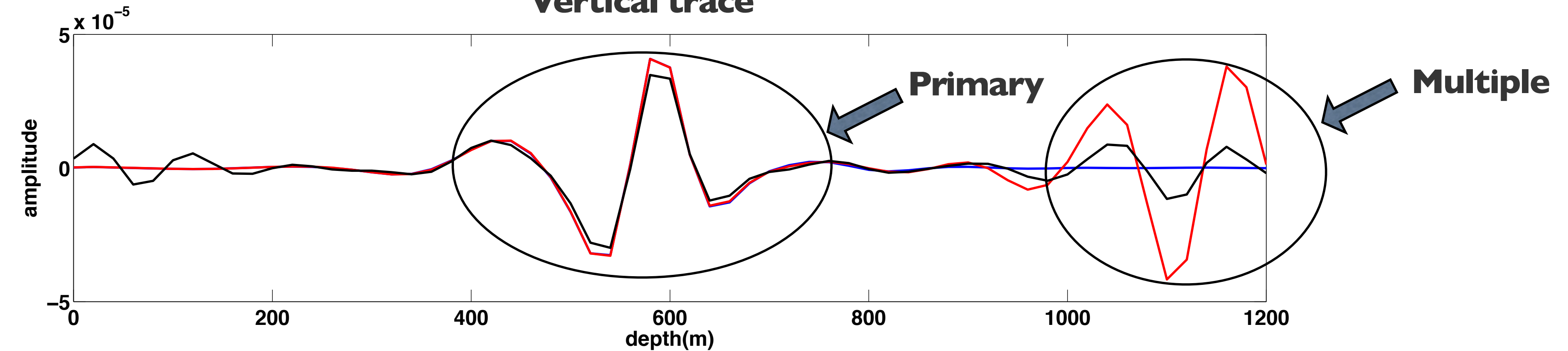
data with multiple,
no aerial source



data with multiple,
aerial source



Vertical trace



Acknowledgements

Thank you for your attention !

<https://www.slim.eos.ubc.ca/>



SINBAD



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